

单通道 12 位 750MSPs 接收器和反馈集成电路 (IC)

查询样片: [ADS54T01](#)

特性

- 单通道
- **12 位分辨率**
- **最大时钟速率: 750MSPs**
- **低摆幅满刻度输入: 1.0Vpp**
- 支持高阻抗输入的模拟输入缓冲器
- **输入带宽 (3dB): >1.2GHz**
- **数据输出接口: DDR 低压差分信号 (LVDS)**
- **196 引脚球状引脚栅格阵列 (BGA) 封装 (12x12mm)**
- **功率耗散: 1.2W**
- **$f_{in}=230\text{MHz}$ IF 时的性能**
 - **信噪比 (SNR): 60.7dBFS**
 - **无杂散动态范围 (SFDR): 73dBc**
- **$f_{in}=700\text{MHz}$ IF 时的性能**
 - **SNR: 58.6dBFS**
 - **SFDR: 64dBc**
- **接收模式: 具有低通或高通滤波器的 2 倍抽取**
- **反馈模式: 针对满带宽数字预失真 (DPD) 反馈的猝发模式输出**

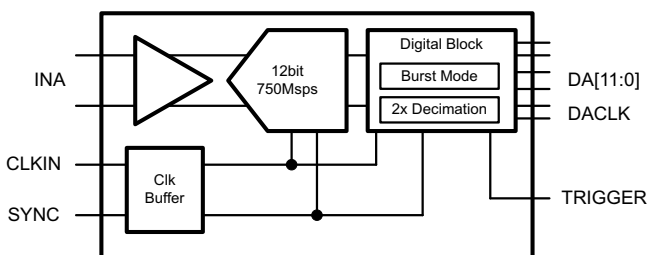
应用范围

- 通信接收器
- 功率放大器线性化

说明

ADS54T01 是一款高线性双通道 12 位, 750MSPs 模数转换器 (ADC), 此器件简化了针对宽带接收器的前端滤波器设计。模拟输入缓冲器使片载跟踪和保持的内部切换不会干扰信号源并提供一个高阻抗输入。

有两个针对输出数据的输出模式-它可被两倍抽取或此数据可在猝发模式中被输出。猝发模式输出特别设计用于 DPD 反馈应用, 在此类应用中, 短时间内高分辨率输出数据可用。此 ADC 设计用于高 SFDR, 且在宽输入频率范围内具有低噪声性能以及出色的无杂散动态范围。此器件采用 196 引脚 BGA 封装并且指定在整个工业温度范围内 (-40°C 至 85°C)。



器件型号	通道数量	速度等级
ADS54T02	2	750MSPs
ADS54T01	1	750MSPs
ADS54T04	2	500MSPs



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

DETAILED BLOCK DIAGRAM

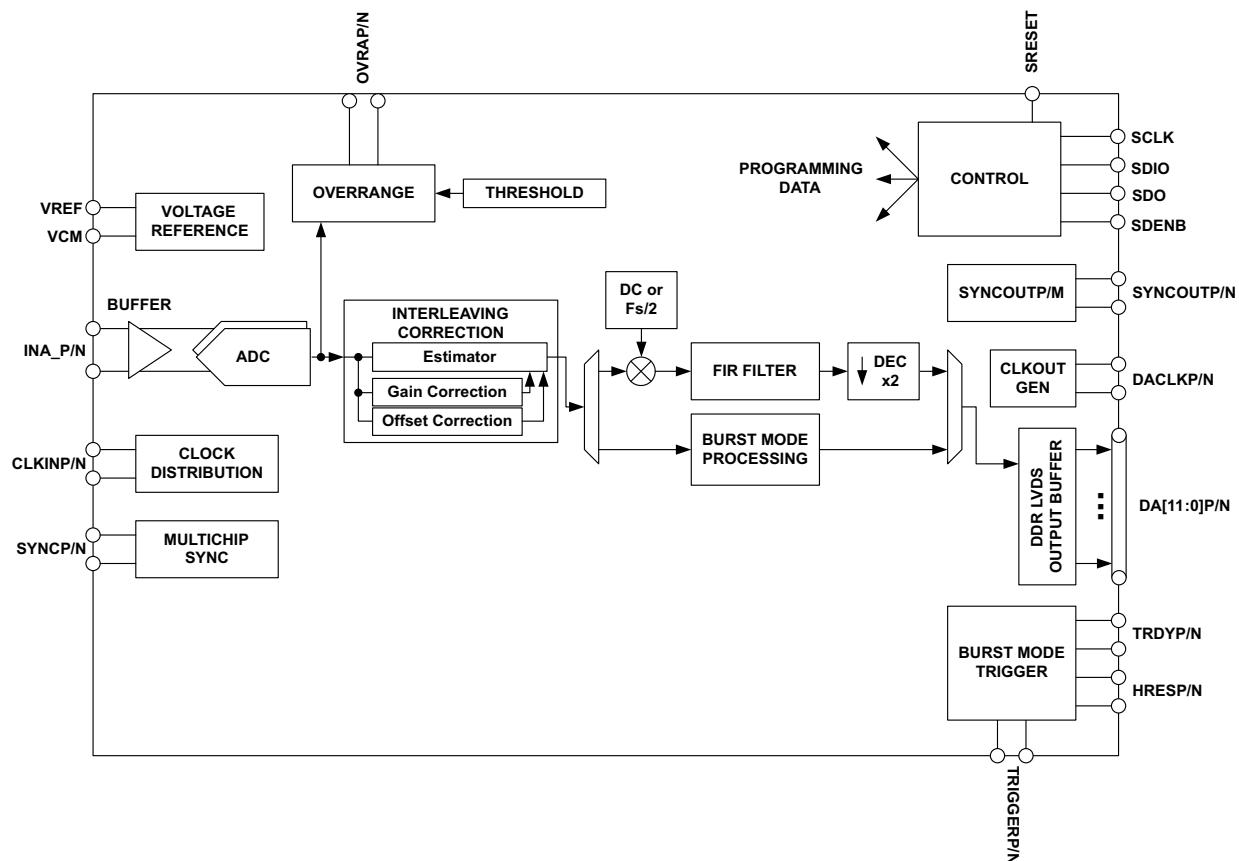


Figure 1. Detailed Block Diagram

PINOUT INFORMATION

	A	B	C	D	E	F	G	H	J	K	L	M	N	P	
14	VREF	VCM	GND	NC	NC	GND	AVDDC	AVDDC	GND	INA_P	INA_N	GND	GND	CLKINP	14
13	SDENB	TEST MODE	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	CLKINN	13
12	SCLK	SRESET	GND	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	AVDD33	GND	AVDD33	AVDD33	12
11	SDIO	ENABLE	GND	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	AVDD18	GND	AVDD18	AVDD18	11
10	SDO	IOVDD	GND	AVDD18	GND	GND	GND	GND	GND	GND	AVDD18	GND	TRIGGER N	TRIGGER P	10
9	DVDD	DVDD	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	SYNCN	SYNCP	9
8	DVDD	DVDD	DVDD	DVDD	GND	GND	GND	GND	GND	GND	DVDD	DVDD	DVDD	DVDD	8
7	NC	NC	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	TRDYN	TRDYP	7
6	NC	NC	DVDD LVDS	DVDD LVDS	GND	GND	GND	GND	GND	GND	DVDD LVDS	DVDD LVDS	HRESN	HRESP	6
5	NC	NC	NC	NC	GND	GND	GND	GND	GND	GND	OVRAN	OVRAP	SYNC OUTN	SYNC OUTP	5
4	NC	NC	NC	NC	NC	NC	NC	DA0P	DA2P	DA4P	DA6P	DA8P	NC	NC	4
3	NC	NC	NC	NC	NC	NC	NC	DA0N	DA2N	DA4N	DA6N	DA8N	DA11N	DA11P	3
2	NC	NC	NC	NC	NC	NC	NC	DACLKP	DA1P	DA3P	DA5P	DA7P	DA10N	DA10P	2
1	NC	NC	NC	NC	NC	NC	NC	DACLKN	DA1N	DA3N	DA5N	DA7N	DA9N	DA9P	1
	A	B	C	D	E	F	G	H	J	K	L	M	N	P	

Figure 2. Pinout in DDR Output Mode (top down view)

PIN ASSIGNMENTS

PIN		I/O	DESCRIPTION
NAME	NUMBER		
INPUT/REFERENCE			
INA_P/N	K14, L14	I	Analog ADC differential input signal.
VCM	B14	O	Output of the analog input common mode (nominally 1.9V). A 0.1μF capacitor to AGND is recommended, but not required.
VREF	A14	I	Reference voltage input. A 0.1μF capacitor to AGND is recommended.
CLOCK/SYNC			
CLKINP/N	P14, P13	I	Differential input clock
SYNCP/N	P9, N9	I	Synchronization input. Inactive if logic low. When clocked in a high state initially, this is used for resetting internal clocks and digital logic and starting the SYNCOUT signal. Internal 100Ω termination.
CONTROL/SERIAL			
SRESET	B12	I	Serial interface reset input. Active low. Initialized internal registers during high to low transition. Asynchronous. Internal 50kΩ pull up resistor to IOVDD.
ENABLE	B11	I	Chip enable – active high. Power down function can be controlled through SPI register assignment. Internal 50kΩ pull up resistor to IOVDD.

PIN ASSIGNMENTS (continued)

PIN		I/O	DESCRIPTION
NAME	NUMBER		
SCLK	A12	I	Serial interface clock. Internal 50kΩ pull-down resistor.
SDIO	A11	I/O	Bi-directional serial data in 3 pin mode (default). In 4-pin interface mode (register x00, D16), the SDIO pin in an input only. Internal 50kΩ pull-down.
SDENB	A13	I	Serial interface enable. Internal 50kΩ pull-down resistor.
SDO	A10	O	Uni-directional serial interface data in 4 pin mode (register x00, D16). The SDO pin is tri-stated in 3-pin interface mode (default). Internal 50kΩ pull-down resistor.
TESTMODE	B13	–	Factory internal test, do not connect
DATA INTERFACE			
DA[11:0]P/N	P3, N3, P2, N2, P1, N1, M4, M3, M2, M1, L4, L3, L2, L1, K4, K3, K2, K1, J4, J3, J2, J1, H4, H3	O	ADC A Data Bits 11 (MSB) to 0 (LSB) in DDR output mode. Standard LVDS output.
DACLKP/N	H2, H1	O	DDR differential output data clock for Bus A. Register programmable to provide either rising or falling edge to center of stable data nominal timing.
SYNCOUPT/N	P5, N5	O	Synchronization output signal for synchronizing multiple ADCs. Can be disabled via SPI.
OVRA/P/N	M5, L5	O	Bus A, Overrange indicator, LVDS output. A logic high signals an analog input in excess of the full-scale range. Optional SYNC output.
TRIGGERP/N	P10, N10	I	Trigger used for High resolution output data in feedback mode. Internal 100Ω termination
TRDYP/N	G4, G3	O	Trigger ready output indicator
HRESP/N	P6, N6	O	Indicator for high resolution output data– logic high signals 12bit output data.
NC	E3, E4, N4, P4	–	Don't connect to pin
POWER SUPPLY			
AVDD33	D12, E12, F12, G12, H12, J12, K12, L12, N12, P12	I	3.3V analog supply
AVDDC	G14, H14	I	1.8V supply for clock input
AVDD18	D10, D11, E11, F11, G11, H11, J11, K11, L10, L11, N11, P11	I	1.8V analog supply
DVDD	A8, A9, B8, B9, C8, D8, L8, M8, N8, P8	I	1.8V supply for digital block
DVDDLVD	C6, C7, D6, D7, L6, L7, M6, M7	I	1.8V supply for LVDS outputs
IOVDD	B10	I	1.8V for digital I/Os
GND		I	Ground

PACKAGE/ORDERING INFORMATION

PRODUCT	PACKAGE-LEAD	PACKAGE DESIGNATOR	SPECIFIED TEMPERATURE RANGE	ECO PLAN ⁽²⁾	LEAD/BALL FINISH	PACKAGE MARKING	ORDERING NUMBER	TRANSPORT MEDIA, QUANTITY
ADS54T01	196-BGA	ZAY	–40°C to 85°C	GREEN (RoHS & no Sb/Br)		ADS54T01I	ADS54T01IZAY	Tray
							ADS54T01IZAYR	Tape and Reel

ABSOLUTE MAXIMUM RATINGS

over operating free-air temperature range (unless otherwise noted)

		VALUE		UNIT
		MIN	MAX	
Supply voltage range, AVDD33		–0.5	4	V
Supply voltage range, AVDDC		–0.5	2.3	V
Supply voltage range, AVDD18		–0.5	2.3	V
Supply voltage range, DVDD		–0.5	2.3	V
Supply voltage range, DVDDLVD		–0.5	2.3	V
Supply voltage range, IOVDD		–0.5	4	V
Voltage applied to input pins	INA_P, INA_N	–0.5	AVDD33 + 0.5	V
	CLKINP, CLKINN	–0.5	AVDDC + 0.5	V
	SYNCP, SYNCN	–0.5	AVDD33 + 0.5	V
	SRESET, SDENB, SCLK, SDIO, SDO, ENABLE	–0.5	IOVDD + 0.5	V
Operating free-air temperature range, T _A		–40	85	°C
Operating junction temperature range, T _J			150	°C
Storage temperature range		–65	150	°C
ESD, Human Body Model			2	kV

THERMAL INFORMATION

THERMAL METRIC ⁽¹⁾		ADS54T01	UNITS
		nFBGA (196-PIN)	
θ_{JA}	Junction-to-ambient thermal resistance ⁽²⁾	37.6	°C/W
θ_{JCTop}	Junction-to-case (top) thermal resistance ⁽³⁾	6.8	
θ_{JB}	Junction-to-board thermal resistance ⁽⁴⁾	16.8	
Ψ_{JT}	Junction-to-top characterization parameter ⁽⁵⁾	0.2	
Ψ_{JB}	Junction-to-board characterization parameter ⁽⁶⁾	16.4	

(1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

(2) The junction-to-ambient thermal resistance under natural convection is obtained in a simulation on a JEDEC-standard, high-K board, as specified in JESD51-7, in an environment described in JESD51-2a.

(3) The junction-to-case (top) thermal resistance is obtained by simulating a cold plate test on the package top. No specific JEDEC-standard test exists, but a close description can be found in the ANSI SEMI standard G30-88.

(4) The junction-to-board thermal resistance is obtained by simulating in an environment with a ring cold plate fixture to control the PCB temperature, as described in JESD51-8.

(5) The junction-to-top characterization parameter, Ψ_{JT} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

(6) The junction-to-board characterization parameter, Ψ_{JB} , estimates the junction temperature of a device in a real system and is extracted from the simulation data for obtaining θ_{JA} , using a procedure described in JESD51-2a (sections 6 and 7).

RECOMMENDED OPERATING CONDITIONS

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM	MAX	UNIT
T_J	Recommended operating junction temperature			105	°C
	Maximum rated operating junction temperature ⁽¹⁾	125			
T_A	Recommended free-air temperature	–40	25	85	°C

(1) Prolonged use at this junction temperature may increase the device failure-in-time (FIT) rate.

ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = 85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVS/IOVDD = 1.8V, –1dBFS differential input (unless otherwise noted).

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNITS
ADC Clock Frequency				40		750	MSPS
Resolution				12			Bits
SUPPLY							
AVDD33				3.15	3.3	3.45	V
AVDDC, AVDD18, DVDD, DVDDLVS				1.7	1.8	1.9	V
IOVDD				1.7	1.8	3.45	V
POWER SUPPLY							
I _{AVDD33}	3.3V Analog supply current				154	170	mA
I _{AVDD18}	1.8V Analog supply current				66	80	mA
I _{AVDDC}	1.8V Clock supply current				42	60	mA
I _{DVDD}	1.8V Digital supply current	Auto Correction Enabled			250	280	mA
I _{DVDD}	1.8V Digital supply current	Auto Correction Disabled			215		mA
I _{DVDD}	1.8V Digital supply current	Auto Correction Disabled, decimation filter enabled			234		mA
I _{DVDDLVS}	1.8V LVDS supply current				66	90	mA
I _{IOVDD}	1.8V I/O Voltage supply current				1	2	mA
P _{dis}	Total power dissipation	Auto Correction Enabled, decimation filter disabled			1.28	1.75	W
P _{dis}	Total power dissipation	Auto Correction Disabled, decimation filter disabled			1.2		W
PSRR		250kHz to 500MHz		40			dB
Shut-down power dissipation					7		mW
Shut-down wake up time					2.5		ms
Standby power dissipation					7		mW
Standby wake up time					100		μs
Deep-sleep mode power dissipation	Auto correction disabled			350			mW
	Auto correction enabled			475			mW
Deep-sleep mode wakeup time					20		μs
Light-sleep mode power dissipation	Auto correction disabled			655			mW
	Auto correction enabled			780			mW
Light-sleep mode wakeup time					2		μs

ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = 85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, AVDD3V = 3.3V, AVDD/DRVDD/IOVDD = 1.8V, –1dBFS differential input (unless otherwise noted).

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
ANALOG INPUTS					
Differential input full-scale			1.0	1.25	V _{pp}
Input common mode voltage			1.9	±0.1	V
Input resistance	Differential at DC		1		kΩ
Input capacitance	Each input to GND		2		pF
VCM common mode voltage output			1.9		V
Analog input bandwidth (3dB)			1200		MHz
DYNAMIC ACCURACY					
Offset Error	Auto Correction Disabled	–20	–7.5	20	mV
	Auto Correction Enabled	–1	0	1	mV
Offset temperature coefficient			–6.5		μV/°C
Gain error		–5		5	%FS
Gain temperature coefficient			0.005		%FS/°C
Differential nonlinearity	$f_{\text{IN}} = 230 \text{ MHz}$	–1	±0.9	2	LSB
Integral nonlinearity	$f_{\text{IN}} = 230 \text{ MHz}$	–5	±1.5	5	LSB
CLOCK INPUT					
Input clock frequency		40		750	MHz
Input clock amplitude			2		V _{pp}
Input clock duty cycle		40%	50%	60%	
Internal clock biasing			0.9		V

ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = 85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVS/IOVDD = 1.8V, -1dBFS differential input (unless otherwise noted).

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	UNITS
Auto Correction			Enabled			Disabled			Vpp
DYNAMIC AC CHARACTERISTICS ⁽¹⁾ – Burst Mode Enabled: 12bit High Resolution Output Data									
SNR	Signal to Noise Ratio	f _{IN} = 10 MHz		61.1			61.2		dBFS
		f _{IN} = 100 MHz		61.1			61.1		
		f _{IN} = 230 MHz	59	60.7			60.9		
		f _{IN} = 450 MHz		59.9			60.5		
		f _{IN} = 700 MHz		58.6			59.6		
HD2,3	Second and third harmonic distortion	f _{IN} = 10 MHz		81			83		dBc
		f _{IN} = 100 MHz		76			81		
		f _{IN} = 230 MHz		78			79		
		f _{IN} = 450 MHz		75			76		
		f _{IN} = 700 MHz		74			76		
Non HD2,3	Spur Free Dynamic Range (excluding second and third harmonic distortion)	f _{IN} = 10 MHz		78			79		dBc
		f _{IN} = 100 MHz	68	75			77		
		f _{IN} = 230 MHz		73			73		
		f _{IN} = 450 MHz		68			69		
		f _{IN} = 700 MHz		64			66		
IL	Fs/2-Fin interleaving spur	f _{IN} = 10 MHz		90			87		dBc
		f _{IN} = 100 MHz		84			82		
		f _{IN} = 230 MHz	65	79			76		
		f _{IN} = 450 MHz		72			72		
		f _{IN} = 700 MHz		66			69		
SINAD	Signal to noise and distortion ratio	f _{IN} = 10 MHz		61.0			61.1		dBc
		f _{IN} = 100 MHz		60.8			61.0		
		f _{IN} = 230 MHz	57.5	60.5			60.8		
		f _{IN} = 450 MHz		59.8			60.3		
		f _{IN} = 700 MHz		58.4			59.4		
THD	Total Harmonic Distortion	f _{IN} = 10 MHz		76			76		dBc
		f _{IN} = 100 MHz		73			76		
		f _{IN} = 230 MHz	66	74			74		
		f _{IN} = 450 MHz		74			73		
		f _{IN} = 700 MHz		72			74		
IMD3	Inter modulation distortion	F _{in} = 184.5 and 185.5MHz, -7dBFS		82			83		dBFS
		F _{in} = 549.5 and 550.5MHz, -7dBFS		76			77		
	Crosstalk			90			90		dB
ENOB	Effective number of bits	f _{IN} = 230 MHz		9.8			9.8		LSB

(1) SFDR and SNR calculations do not include the DC or Fs/2 bins when Auto Correction is disabled.

ELECTRICAL CHARACTERISTICS

Typical values at $T_A = 25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = 85^\circ\text{C}$, ADC sampling rate = 500Msps, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVD/IOVDD = 1.8V, –1dBFS differential input (unless otherwise noted).

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
OVER-DRIVE RECOVERY ERROR					
Input overload recovery	Recovery to within 5% (of final value) for 6dB overload with sine wave input		2		ns
SAMPLE TIMING CHARACTERISTICS					
rms Aperture Jitter	Sample uncertainty		100		fs rms
Data Latency	ADC sample to digital output, Auto correction disabled		38		Clock Cycles
	ADC sample to digital output, Auto correction enabled		50		
	ADC sample to digital output, Decimation filter enabled, Auto correction disabled		74		Sampling clock Cycles
Over-range Latency	ADC sample to over-range output		12		Clock Cycles

ELECTRICAL CHARACTERISTICS

The DC specifications refer to the condition where the digital outputs are not switching, but are permanently at a valid logic level 0 or 1. AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVD/IOVDD = 1.8V

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS	
DIGITAL INPUTS – SRESET, SCLK, SDENB, SDIO, ENABLE						
High-level input voltage	All digital inputs support 1.8V and 3.3V logic levels.	0.7 x IOVDD			V	
Low-level input voltage		0.3 x IOVDD		V		
High-level input current		–50	200		μA	
Low-level input current		–50	50		μA	
Input capacitance		5			pF	
DIGITAL OUTPUTS – SDO						
High-level output voltage	Iload = -100uA	IOVDD – 0.2			V	
	Iload = -2mA	0.8 x IOVDD				
Low-level output voltage	Iload = 100uA	0.2			V	
	Iload = 2mA	0.22 x IOVDD				
DIGITAL INPUTS – SYNC/P/N, TRIGGER/P/N						
V _{ID}	Differential input voltage	250	350	450	mV	
V _{CM}	Input common mode voltage	1.125	1.2	1.375	V	
t _{SU}		500			ps	
DIGITAL OUTPUTS – DA[11:0]/P/N, DACLK/P/N, OVRAP/N, SYNCOUT/P/N, TRDYP/N, HRESP/N						
V _{OD}	Output differential voltage	Iout = 3.5mA	250	350	450	mV
V _{OCM}	Output common mode voltage	Iout = 3.5mA	1.125	1.25	1.375	V
t _{su}	F _s = 750Msps	Data valid to zero-crossing of DACLK	320	400		ps
t _h	F _s = 750Msps	Zero-crossing of DACLK to data becoming invalid	250	320		ps
t _{PD}	F _s = 750Msps	CLKIN falling edge to DACLK rising edge	3.36	3.69	3.92	ns
t _{RISE}		10% - 90%	100	150	200	ps
t _{FALL}		90% - 10%	100	150	200	ps

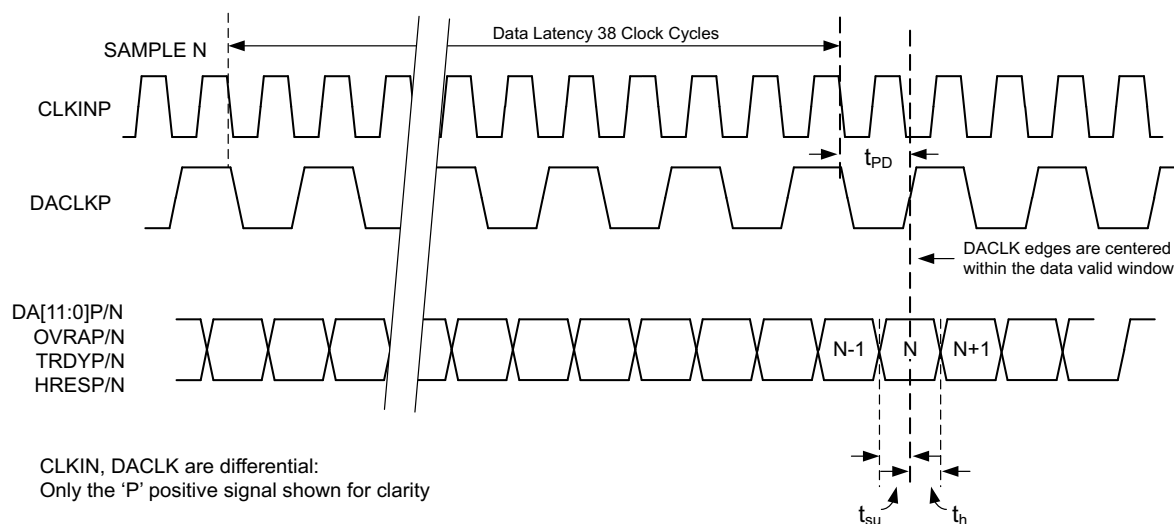


Figure 3. Timing Diagram for 12-bit DDR Output

TYPICAL CHARACTERISTICS

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750Msps, 50% clock duty cycle, $\text{AVDD33} = 3.3\text{V}$, $\text{AVDDC}/\text{AVDD18}/\text{DVDD}/\text{DVDDLVD}/\text{IOVDD} = 1.8\text{V}$, -1dBFS differential input, unless otherwise noted.

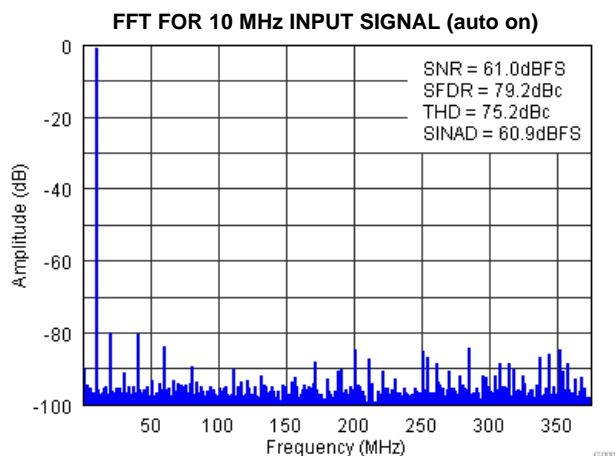


Figure 4.

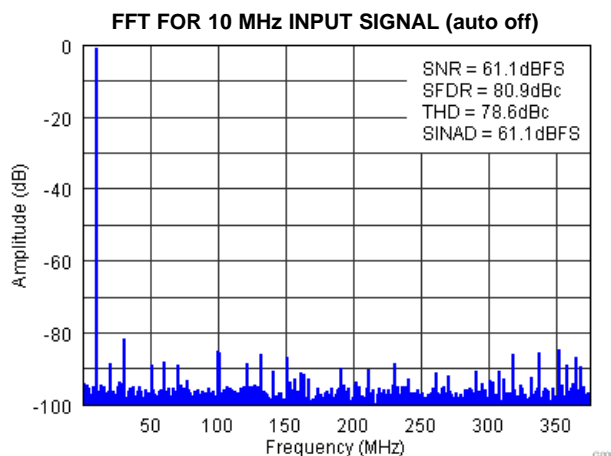


Figure 5.

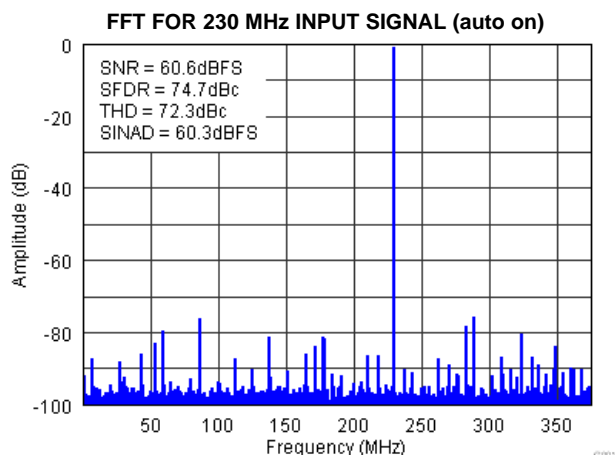


Figure 6.

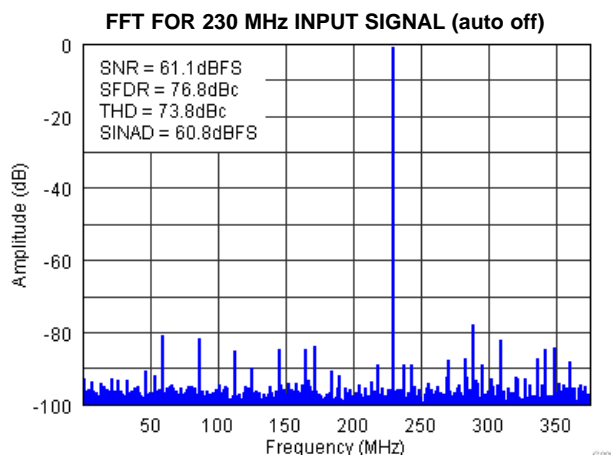


Figure 7.

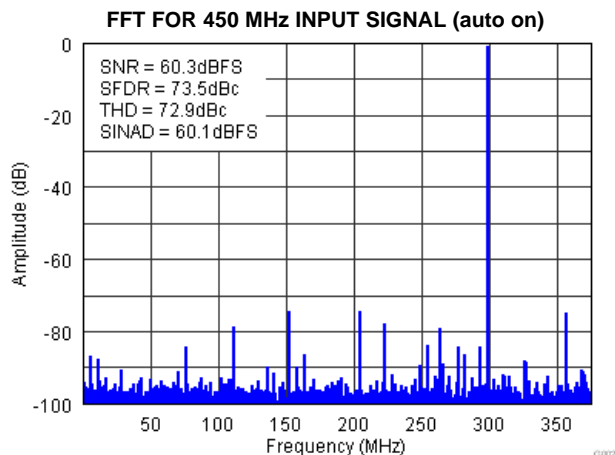


Figure 8.

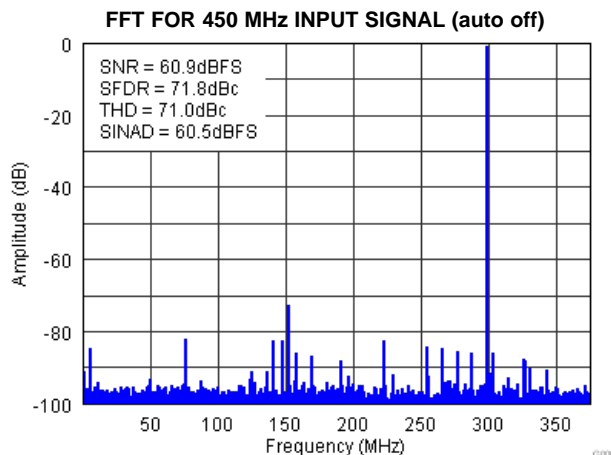


Figure 9.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVS/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

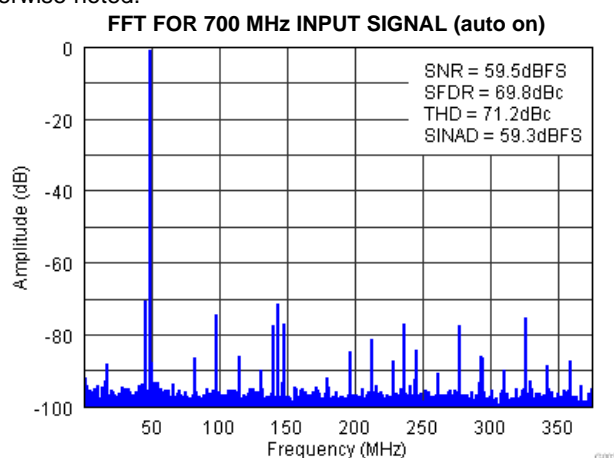


Figure 10.

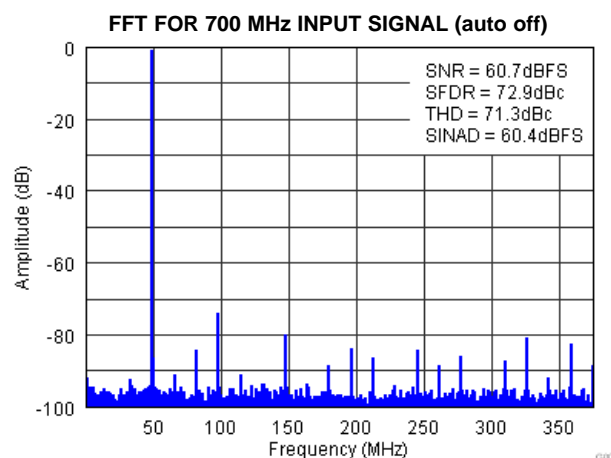


Figure 11.

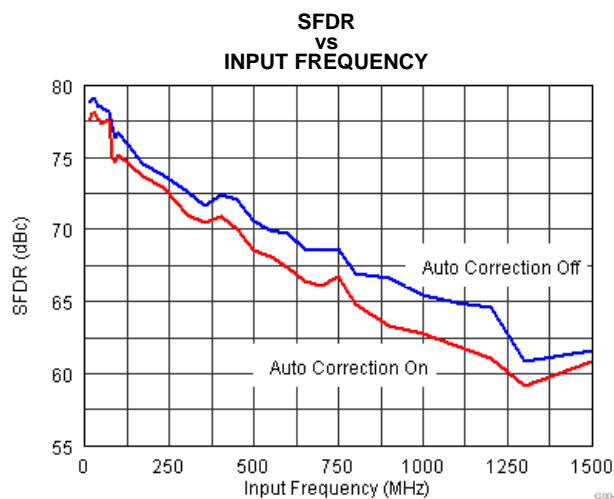


Figure 12.

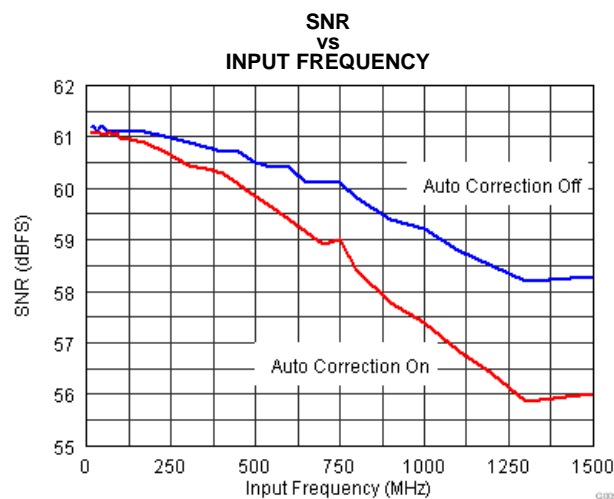


Figure 13.

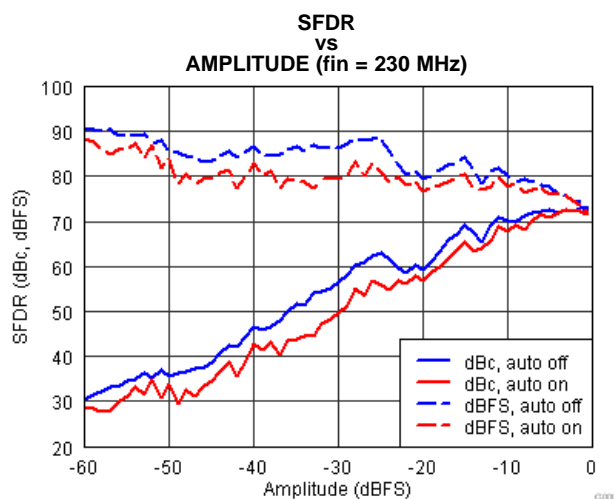


Figure 14.

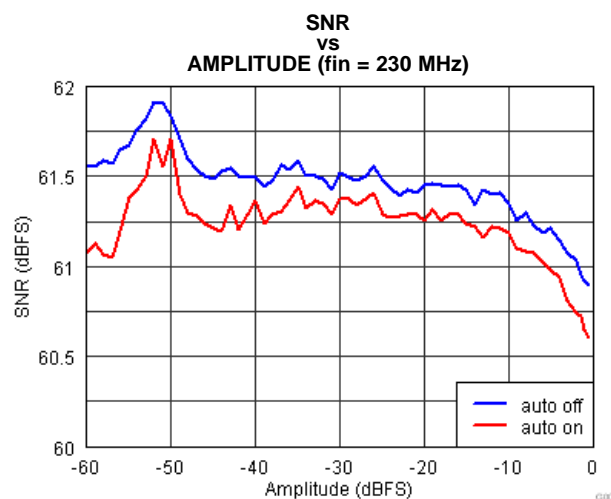


Figure 15.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, $\text{AVDD33} = 3.3\text{V}$, $\text{AVDDC}/\text{AVDD18}/\text{DVDD}/\text{DVDDLVS}/\text{IOVDD} = 1.8\text{V}$, -1dBFS differential input, unless otherwise noted.

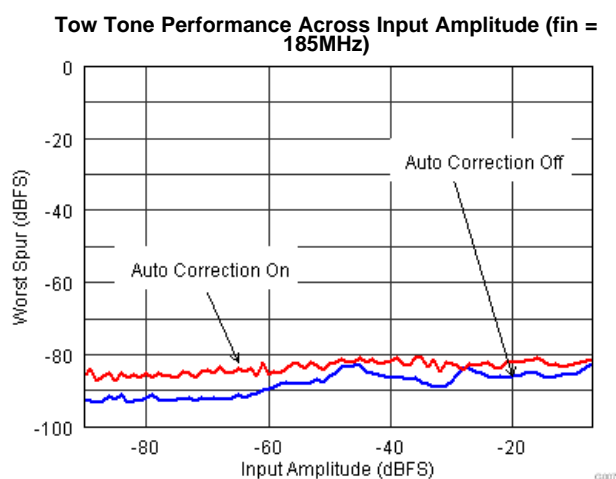


Figure 16.

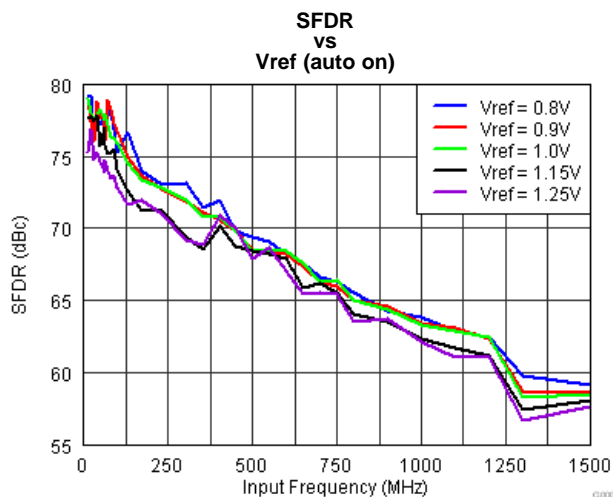


Figure 17.

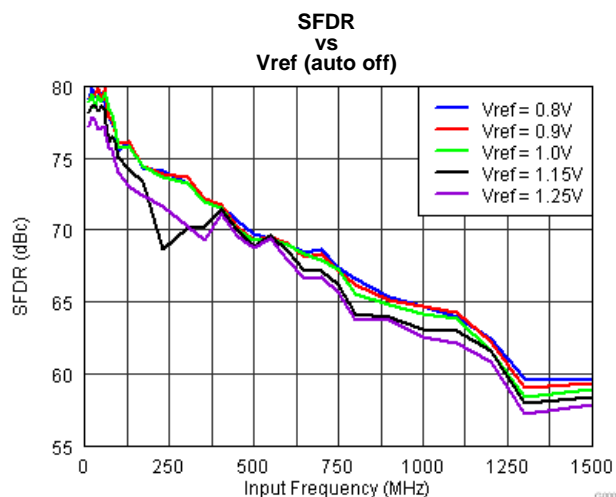


Figure 18.

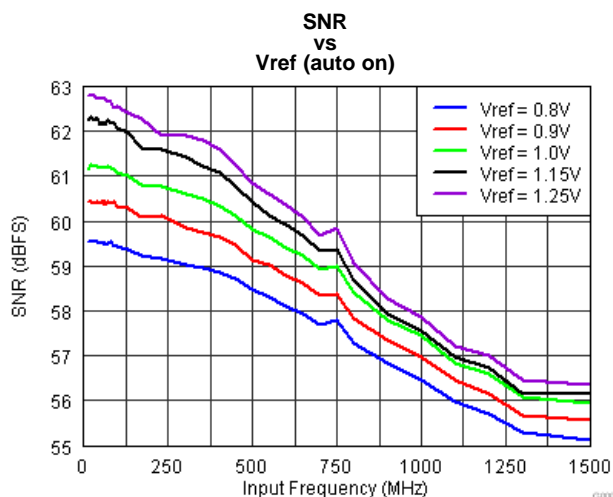


Figure 19.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, $\text{AVDD33} = 3.3\text{V}$, $\text{AVDDC}/\text{AVDD18}/\text{DVDD}/\text{DVDDLVS}/\text{IOVDD} = 1.8\text{V}$, -1dBFS differential input, unless otherwise noted.

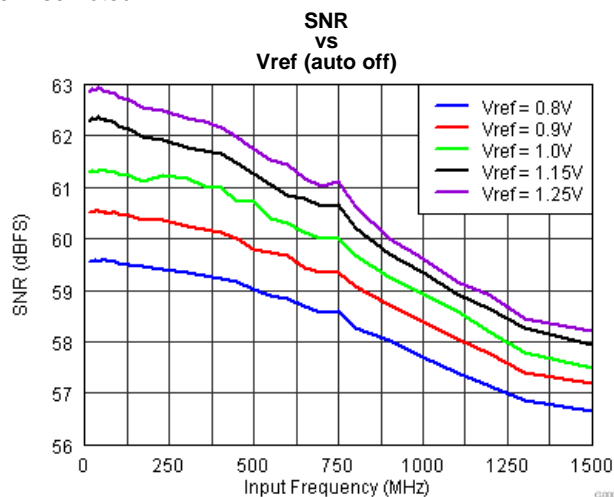


Figure 20.

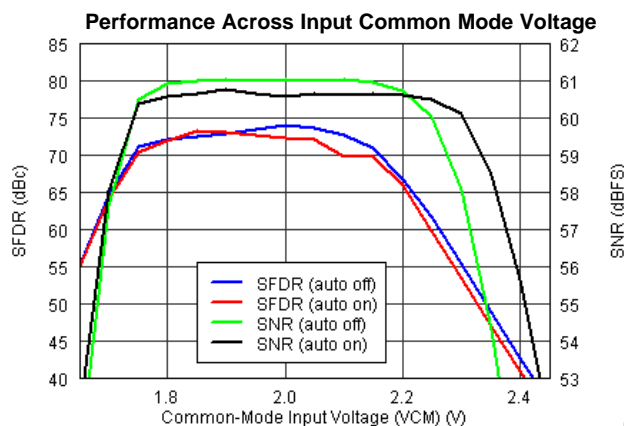


Figure 21.

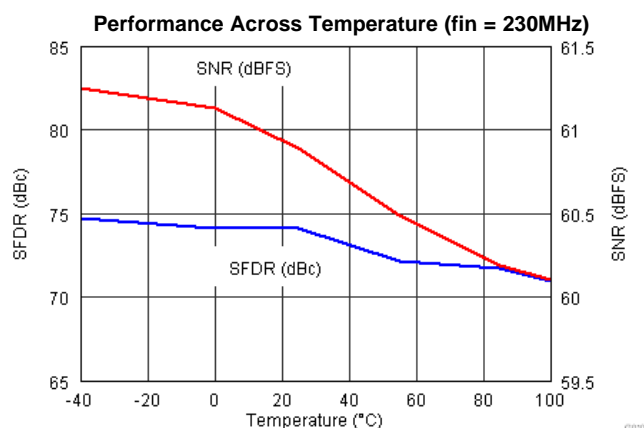


Figure 22.

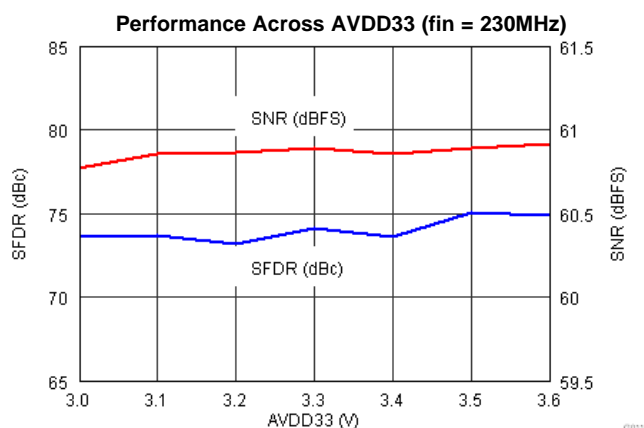


Figure 23.

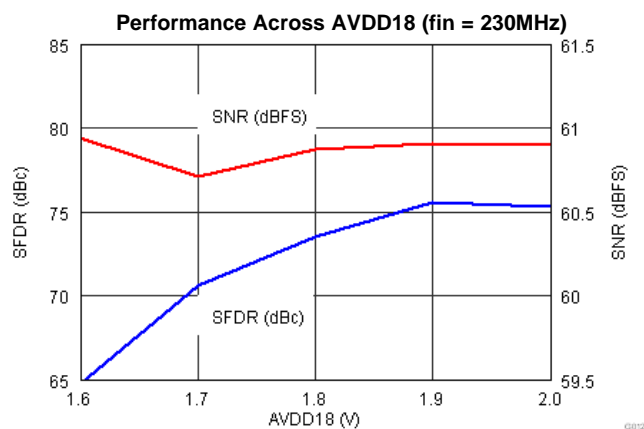


Figure 24.

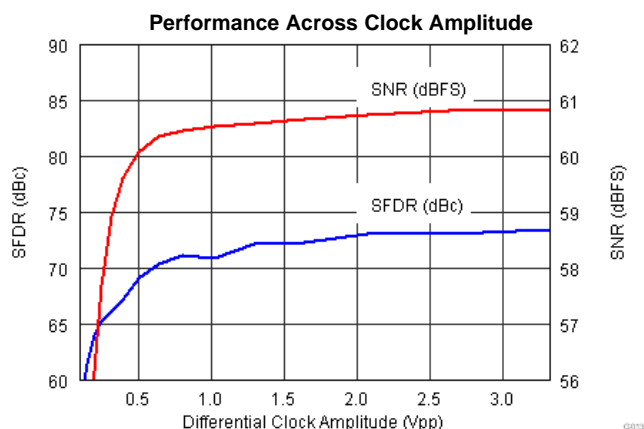


Figure 25.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750Mps, 50% clock duty cycle, $\text{AVDD33} = 3.3\text{V}$, $\text{AVDDC}/\text{AVDD18}/\text{DVDD}/\text{DVDDLVS}/\text{IOVDD} = 1.8\text{V}$, -1dBFS differential input, unless otherwise noted.

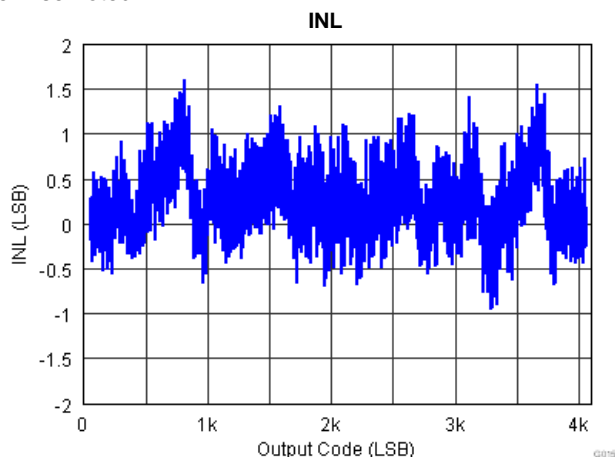


Figure 26.

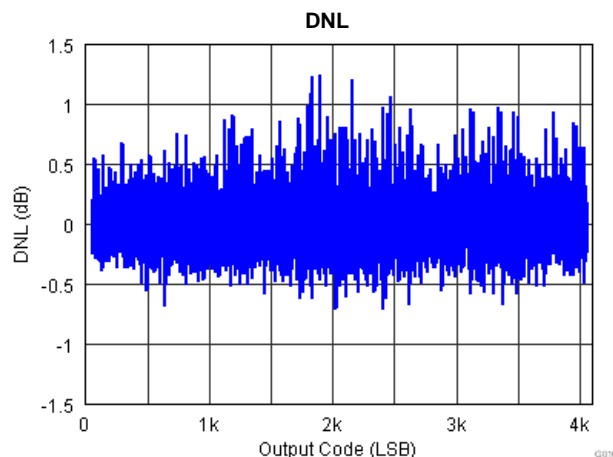


Figure 27.

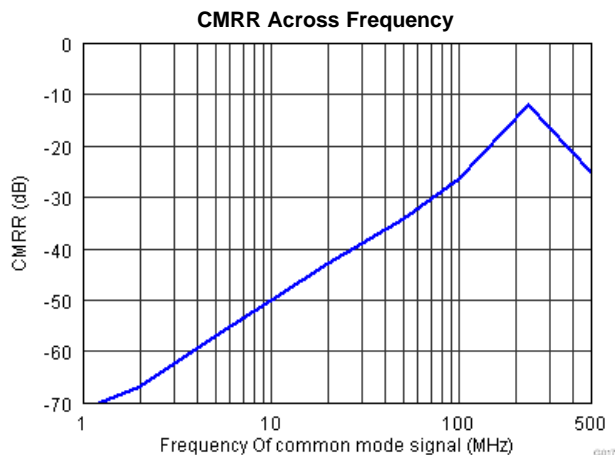


Figure 28.

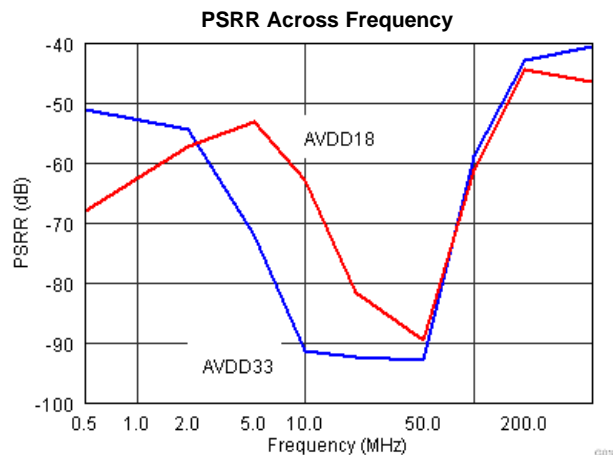


Figure 29.

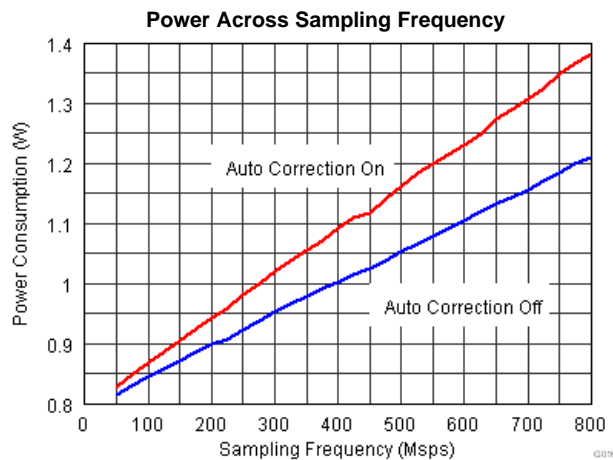


Figure 30.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPS, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVD/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

SFDR Across Input and Sampling Frequencies (auto on)

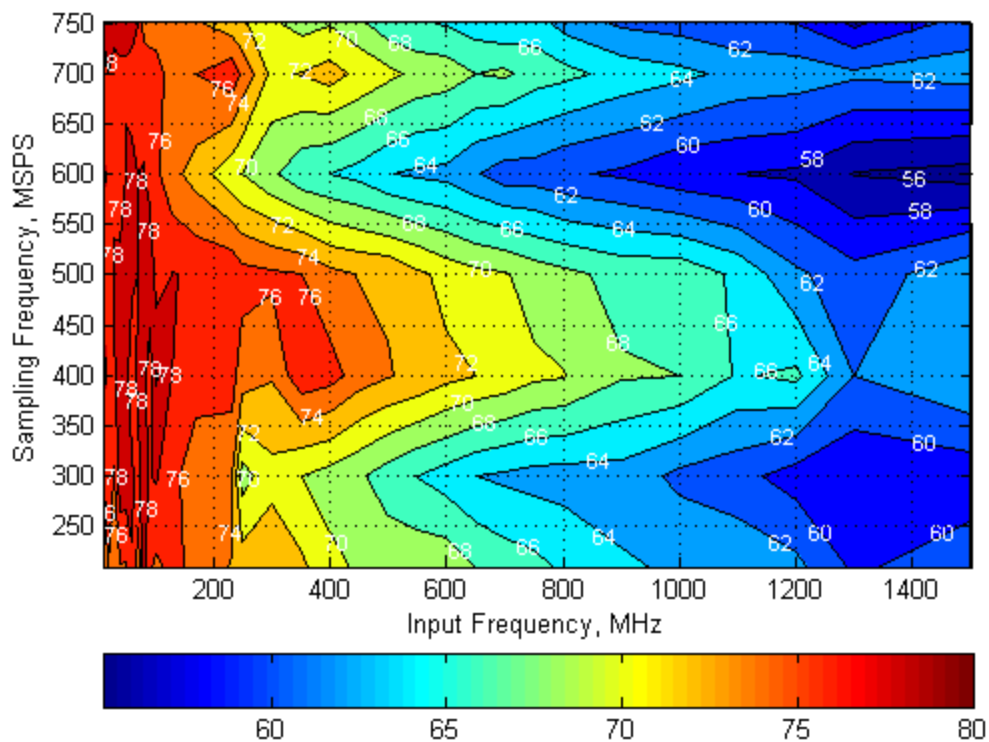


Figure 31.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPs, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDs/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

SFDR Across Input and Sampling Frequencies (auto off)

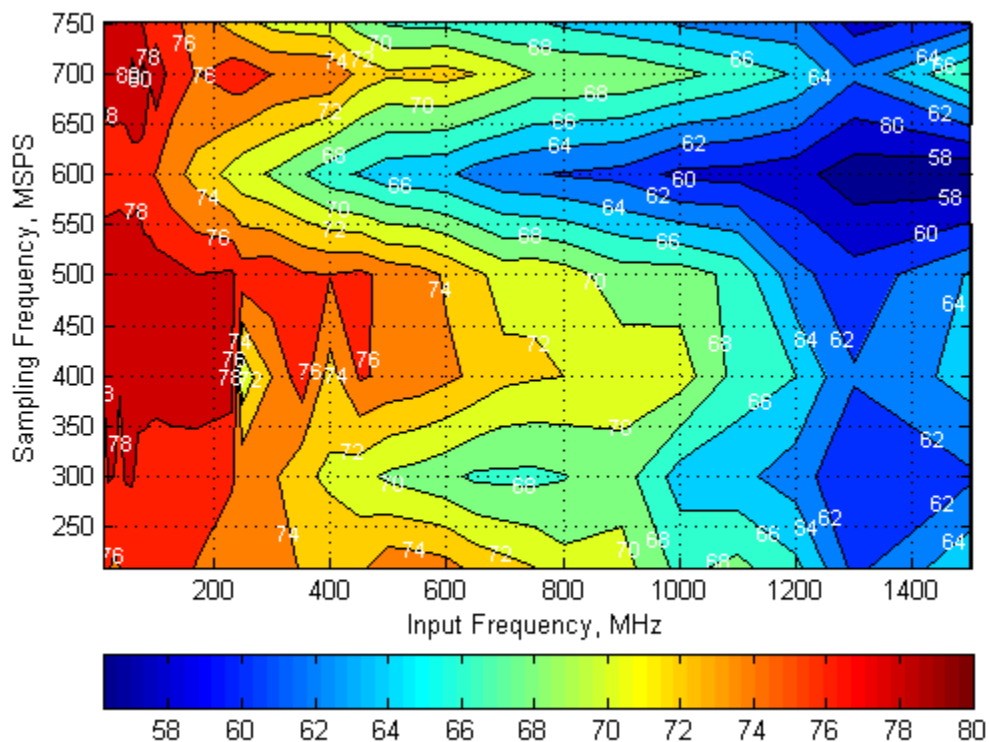
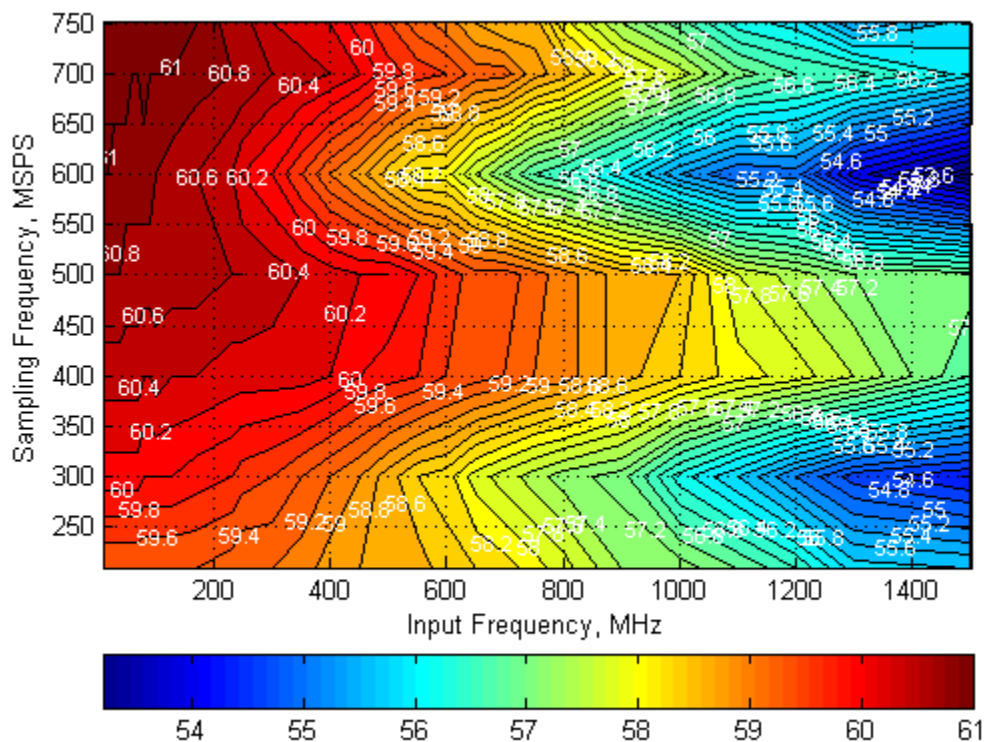


Figure 32.

TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPs, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDs/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

SNR Across Input and Sampling Frequencies (auto on)



TYPICAL CHARACTERISTICS (continued)

Typical values at $T_A = +25^\circ\text{C}$, full temperature range is $T_{\text{MIN}} = -40^\circ\text{C}$ to $T_{\text{MAX}} = +85^\circ\text{C}$, ADC sampling rate = 750MSPs, 50% clock duty cycle, AVDD33 = 3.3V, AVDDC/AVDD18/DVDD/DVDDLVDs/IOVDD = 1.8V, -1dBFS differential input, unless otherwise noted.

SNR Across Input and Sampling Frequencies (auto on)

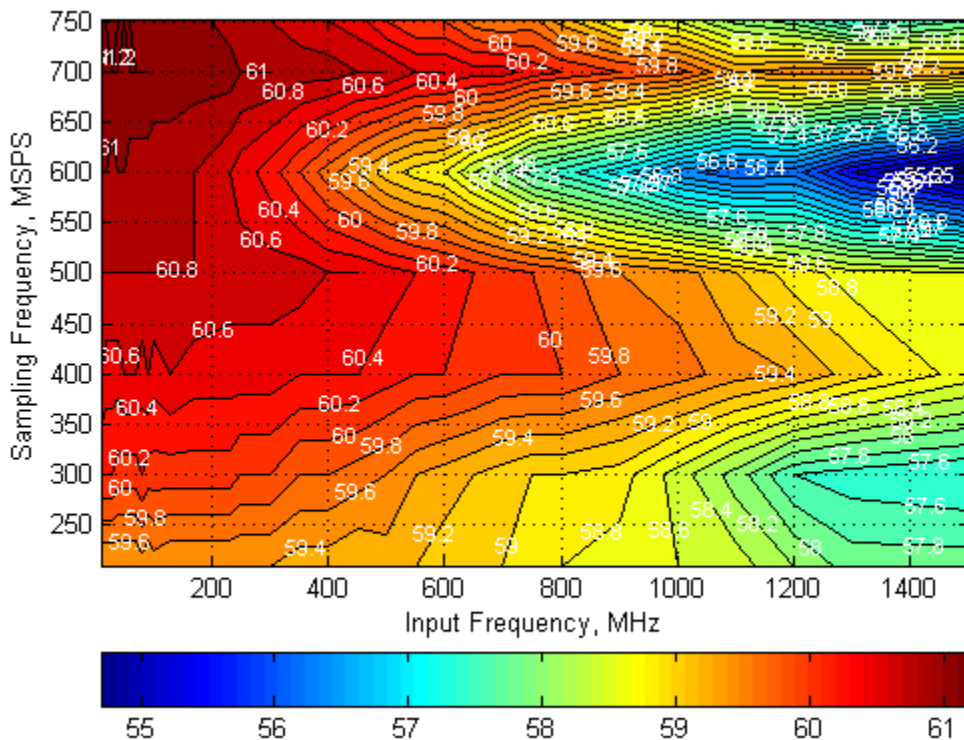


Figure 34.

FEATURES

POWER DOWN MODES

The ADS54T01 can be configured via SPI write (address x37) to a stand-by, light or deep sleep power mode which is controlled by the ENABLE pin. The sleep modes are active when the ENABLE pin goes low. Different internal functions stay powered up which results in different power consumption and wake up time between the two sleep modes.

Sleep mode	Wake up time	Power Consumption Auto correction disabled	Power Consumption Auto correction enabled
Complete Shut Down	2.5 ms	7mW	7mW
Stand-by	100µs	7mW	7mW
Deep Sleep	20µs	350mW	475mW
Light Sleep	2µs	655mW	780mW

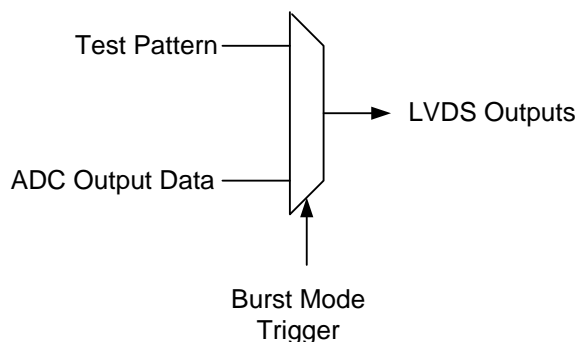
TEST PATTERN OUTPUT

The ADS54T01 can be configured to output different test patterns that can be used to verify the digital interface is connected and working properly.

To enable the test pattern mode, the high performance mode 1 has to be disabled first via SPI register write. Then different test patterns can be selected by configuring registers x3C, x3D and x3E. All three registers must be configured for the test pattern to work properly.

First set HP1 = 0 (Addr 0x01, D01)

Internally the test pattern replaces the sampled data from the ADC. However at the LVDS outputs the output data is still subject to burst mode operation. In low resolution output the LSBs of the test pattern are replaced with 0s.



Register Address	All 0s	All 1s	Toggle (0xAAA => 0x555)	Toggle (0xFFFF => 0x000)
0x3C	0x8000	0xBFFC	0x9554	0xBFFC
0x3D	0x0000	0x3FFC	0x2AA8	0x0000
0x3E	0x0000	0x3FFC	0x1554	0x3FFC

Register Address	Custom Pattern															
	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
x3C	1	0	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	0	0
x3D	0	0													0	0
x3E	0	0													0	0

For normal operation, set HP1 = 1 (Addr 0x01, D01) and 0x3C, 0x3D, 0x3E all to 0.

CLOCK INPUTS

The ADS54T01 clock input can be driven differentially with a sine wave, LVPECL or LVDS source with little or no difference in performance. The common mode voltage of the clock input is set to 0.9V using internal 2kΩ resistors. This allows for AC coupling of the clock inputs. The termination resistors should be placed as close as possible to the clock inputs in order to minimize signal reflections and jitter degradation.

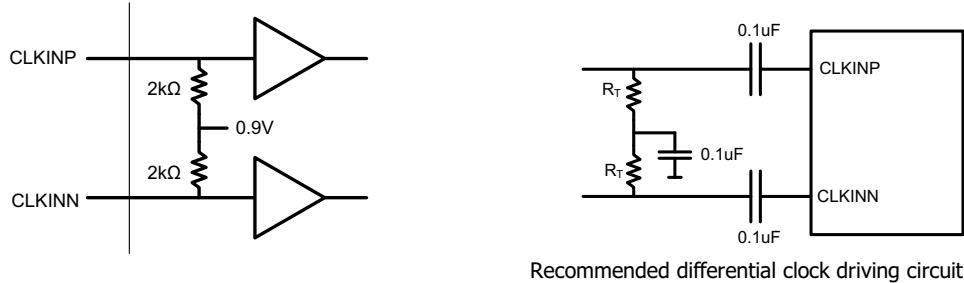


Figure 35. Recommended Differential Clock Driving Circuit

SNR AND CLOCK JITTER

The signal to noise ratio of the ADC is limited by three different factors: the quantization noise is typically not noticeable in pipeline converters and is 72dB for a 12bit ADC. The thermal noise limits the SNR at low input frequencies while the clock jitter sets the SNR for higher input frequencies.

$$\text{SNR}_{\text{ADC}}[\text{dBc}] = -20 \times \log \sqrt{\left(10 - \frac{\text{SNR}_{\text{Quantization_Noise}}}{20}\right)^2 + \left(10 - \frac{\text{SNR}_{\text{ThermalNoise}}}{20}\right)^2 + \left(10 - \frac{\text{SNR}_{\text{Jitter}}}{20}\right)^2} \quad (1)$$

The SNR limitation due to sample clock jitter can be calculated as following:

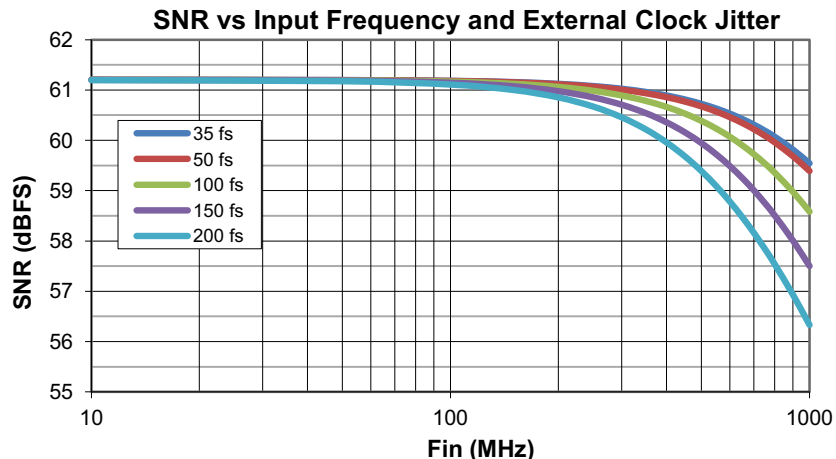
$$\text{SNR}_{\text{Jitter}}[\text{dBc}] = -20 \times \log(2\pi \times f_{\text{IN}} \times t_{\text{jitter}}) \quad (2)$$

The total clock jitter (Tjitter) has three components – the internal aperture jitter (100fs for ADS54T01) which is set by the noise of the clock input buffer, the external clock jitter and the jitter from the analog input signal. It can be calculated as following:

$$T_{\text{jitter}} = \sqrt{(T_{\text{jitter,Ext.Clock_Input}})^2 + (T_{\text{Aperture_ADC}})^2} \quad (3)$$

External clock jitter can be minimized by using high quality clock sources and jitter cleaners as well as bandpass filters at the clock input while a faster clock slew rate improves the ADC aperture jitter.

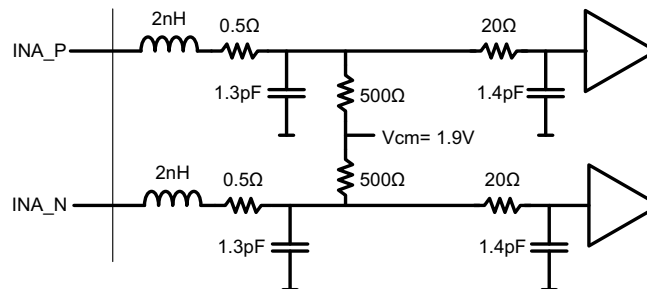
The ADS54T01 has a thermal noise of 61.2 dBFS and internal aperture jitter of 100fs. The SNR depending on amount of external jitter for different input frequencies is shown in the following figure.



ANALOG INPUTS

The ADS54T01 analog signal input is designed to be driven differentially. The analog input pins have internal analog buffers that drive the sampling circuit. As a result of the analog buffer, the input pins present a high impedance input across a very wide frequency range to the external driving source which enables great flexibility in the external analog filter design as well as excellent 50Ω matching for RF applications. The buffer also helps to isolate the external driving circuit from the internal switching currents of the sampling circuit which results in a more constant SFDR performance across input frequencies.

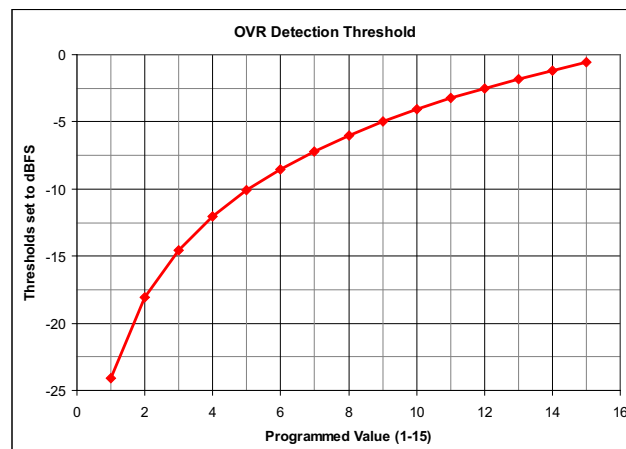
The common-mode voltage of the signal inputs is internally biased to 1.9V using 500Ω resistors which allows for AC coupling of the input drive network. Each input pin (INP, INM) must swing symmetrically between ($V_{CM} + 0.25V$) and ($V_{CM} - 0.25V$), resulting in a 1.0Vpp (default) differential input swing. The input sampling circuit has a 3dB bandwidth that extends up to 1.2GHz.



OVER-RANGE INDICATION

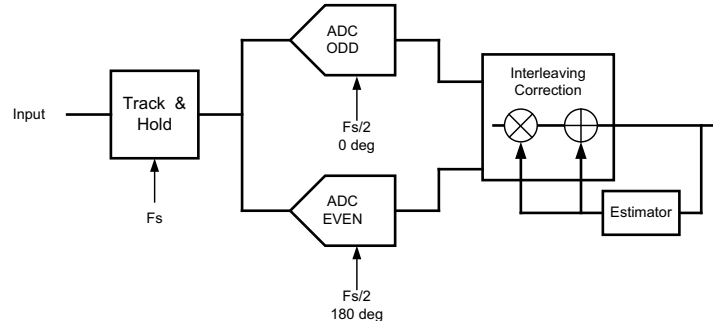
The ADS54T01 provides a fast over-range indication on the OVRA/B pins. The fast OVR is triggered if the input voltage exceeds the programmable overrange threshold and it gets presented after just 12 clock cycles enabling a quicker reaction to an overrange event. The OVR threshold can be configured using SPI register writes.

The input voltage level at which the overload is detected is referred to as the threshold and is programmable using the Over-range threshold bits. The threshold at which fast OVR is triggered is ($\text{full-scale} \times [\text{the decimal value of the FAST OVR THRESH bits}] / 16$). After reset, the default value of the over-range threshold is set to 15 (decimal) which corresponds to a threshold of 0.56dB below full scale ($20 \cdot \log(15/16)$).



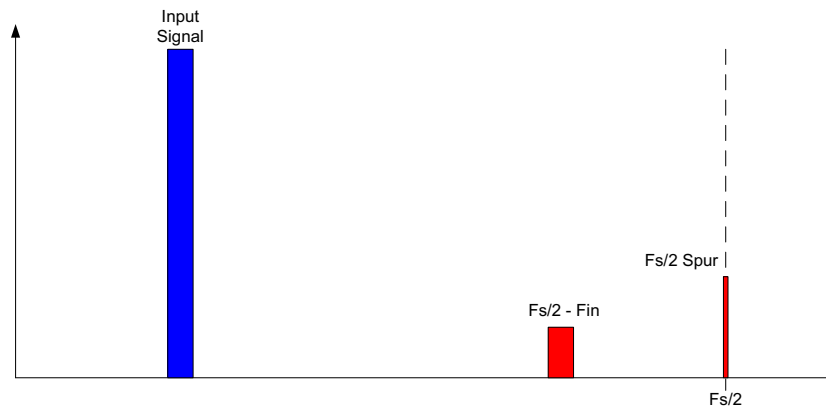
INTERLEAVING CORRECTION

The data converter channel consists of two interleaved ADCs each operating at half of the ADC sampling rate but 180° out of phase from each other. The front end track and hold circuitry is operating at the full ADC sampling rate which minimizes the timing mismatch between the two interleaved ADCs. In addition the ADS54T04 is equipped with internal interleaving correction logic that can be enabled via SPI register write.



The interleaving operation creates 2 distinct and interleaving products:

- $F_s/2 - F_{in}$: this spur is created by gain timing mismatch between the ADCs. Since internally the front end track and hold is operated at the full sampling rate, this component is greatly improved and mostly dependent on gain mismatch.
- $F_s/2$ Spur: due to offset mismatch between ADCs



The auto correction loop can be enabled via SPI register write in address 0x01. By default it is disabled for lowest possible power consumption. The default settings for the auto correction function should work for most applications. However please contact Texas Instruments if further fine tuning of the algorithm is required.

The auto correction function yields best performance for input frequencies below 250MHz.

RECEIVE MODE: DECIMATION FILTER

Each channel has a digital filter in the data path as shown in Figure 36. The filter can be programmed as a low-pass or a high-pass filter and the normalized frequency response of both filters is shown in Figure 37.

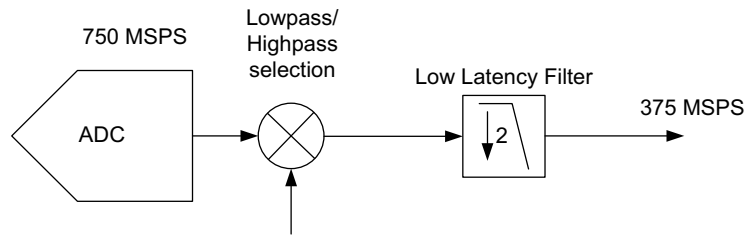


Figure 36.

The decimation filter response has a 0.1dB pass band ripple with approximately 41% pass-band bandwidth. The stop-band attenuation is approximately 40dB.

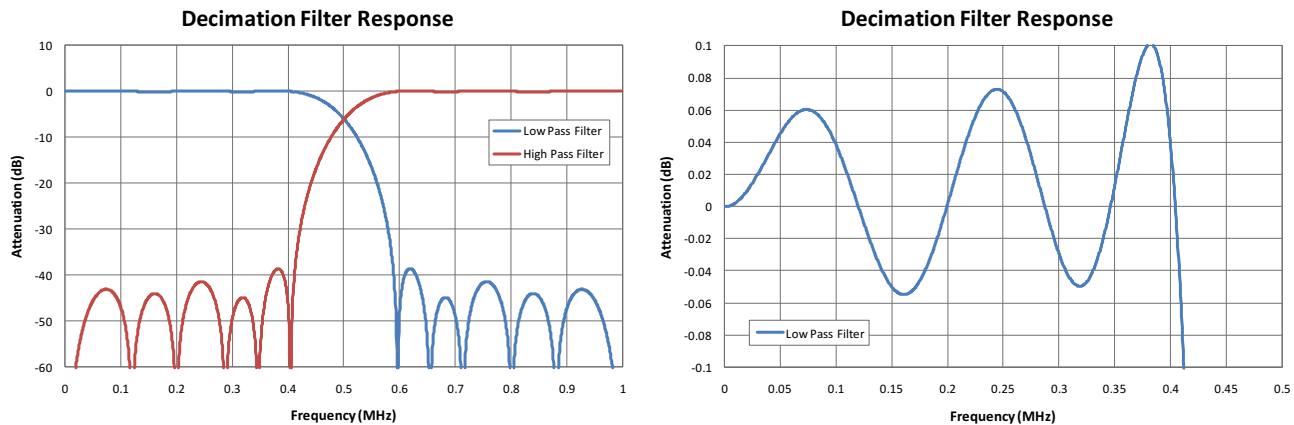


Figure 37.

FEEDBACK MODE: BURST MODE

In burst mode the output data is alternated between a high resolution 12 bit output of 2^N samples and a low resolution 7 or 11bit output of 2^{N+3} samples. Burst mode is enabled through SPI register write and there are two basic operating modes available – a manual trigger mode where the high resolution output is initiated through external trigger and an auto trigger mode where the internal logic transitions to high resolution output immediately after transmitting the last low resolution sample. Upon enabling burst mode through a SPI register write, the ADS54T01 transmits 2^{13} low resolution samples and the trigger command is locked out until completion.

The parameter N can be changed via SPI at any time. It will go in effect with the next output cycle starting with transmission of low resolution samples. The default value for N after reset is N=10.

N limit	10 (minimum)	25 (maximum)
Number of low resolution samples per cycle (2^{N+3})	8,192	268,435,456
Number of high resolution samples per cycle (2^N)	1,024	33,554,432
Total amount of samples per cycle	9,216	301,989,888
Maximum number of high resolution (12-bit) samples per 1 second	83.3M	83.3M

Manual Trigger Mode

The control of the high resolution output is shown below along with the two output flags (TRDY and HRES).

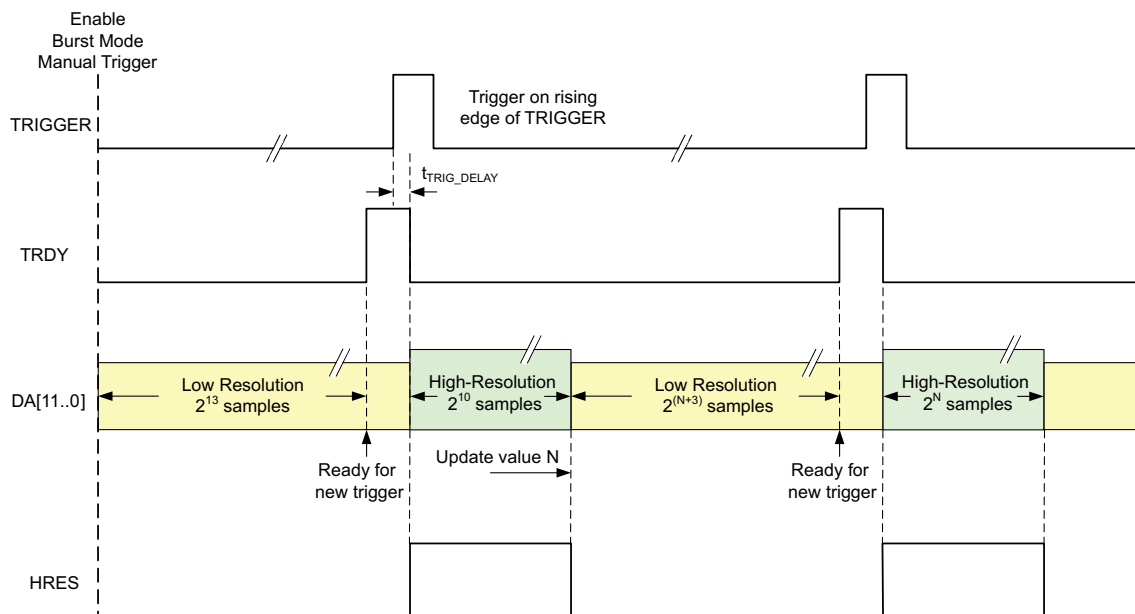


Figure 38. Triggering High Resolution Mode and Lockout Time

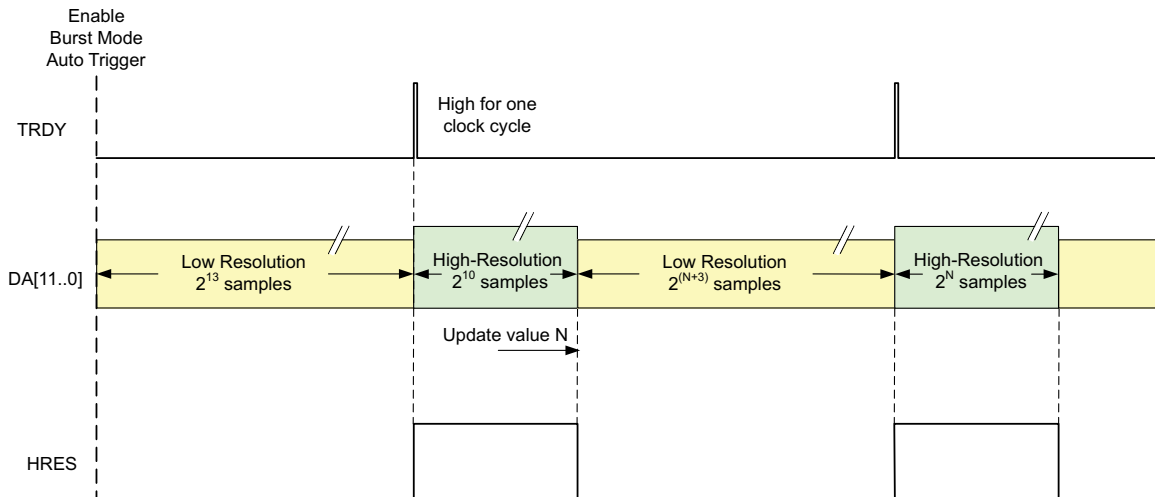
After enabling burst mode, the output data DA[11..0] are forced to low resolution mode for 2^{13} samples. During that period any trigger signal is ignored. The completion of the low resolution sample cycle is signaled by a logic high on the TRDY output pins indicating that a high resolution (12-bit) data output burst can be triggered by a low to high transition on the TRIGGER input. The ADC monitors the TRIGGER input at each rising edge of the input clock.

The high resolution output data starts with a delay of $t_{TRIG_DELAY} = 1-2$ DACLK clock cycles and is indicated through the HRES data flag which stays high for all 2^N high resolution samples. At completion the register value for N is verified and transmission of $2^{(N+3)}$ low resolution data immediately follows. Once the last low resolution sample is output on the output data bus, the flag TRDY is asserted high again indicating the end of the lockout period and the next 2^N high resolution samples can be triggered again.

Auto Trigger Mode

This mode is enabled by setting the auto trigger bit via SPI register write and the DA data outputs start in low resolution for 2^{13} samples. Immediately following completion of transmission of the last low resolution sample, the outputs automatically start transmitting 2^{10} high resolution samples without the need for external trigger ensuring maximum efficiency. Any input signal on the TRIGGER pins is ignored and the TRDY flag will go high only for one clock cycle with the start of the high resolution data.

The output flag HRES is aligned with the 2^N high resolution output samples and the parameter N can be changed until the next output cycle starts again with low resolution output data.



High Resolution Output Data

After trigger, the data outputs DA[11..0] are 12-bit resolution for 2^N samples, where N is a programmable register with a range $10 \leq N \leq 25$ (corresponding to 1024 to 33554432 samples).

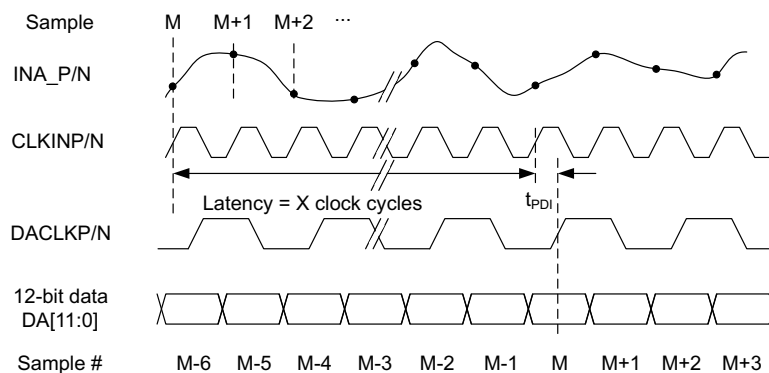


Figure 39. High Resolution Data Output Timing

After the high resolution data, the data output returns to low resolution mode, the logic level of the HRES flag returns low and the trigger is locked out for $2^{(N+3)}$ samples. N is the sample integer resulting in a maximum output duty cycle of 1/9. During the trigger lockout time, a low to high transition on TRIGGERP/N will be ignored. After the 2^{N+3} low resolution samples, the TRIGGERP/N is re-enabled for the next valid data burst.

Low Resolution Output Data

There are two different options for the low resolution output data and the selection is made through SPI register control. The data can either be output at full speed (ADC sampling rate) with the output resolution limited to 7bit (7 MSBs). Alternatively the output resolution can be selected to 11bit (11 MSBs) but at a reduced effective data rate where every 4th sample gets repeated four times.

Full Speed – 7bit

The output data rate and timing is exactly the same as the high resolution data – only the output resolution is limited to the 7 MSBs.

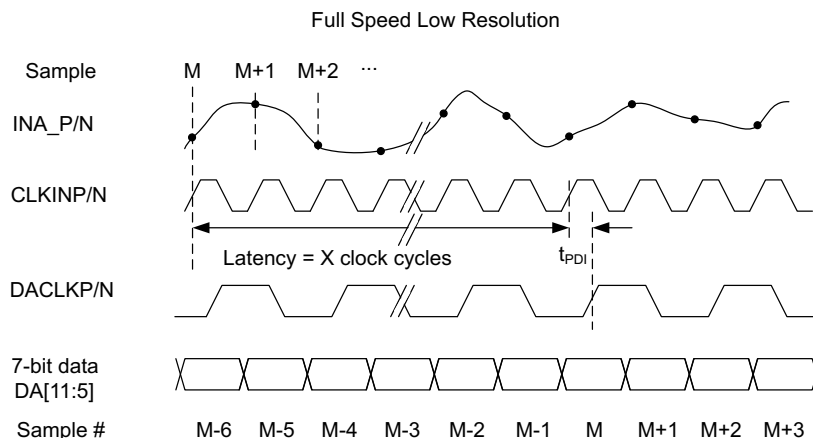


Figure 40. Full Rate Low Resolution Output Data Timing

Decimated Low Resolution Output Data

In decimated low resolution mode the output data is limited to 11-bits and every sample is repeated four times so the effective data rate is 1/4 of ADC sampling rate. The latency of the ADC sample to output sample is exactly the same as for high resolution data – there is no uncertainty in which conversion sample results in the valid output data. This is because the output continues to run at the ADC sample rate – only the resolution is changed and three out of four samples are deleted.

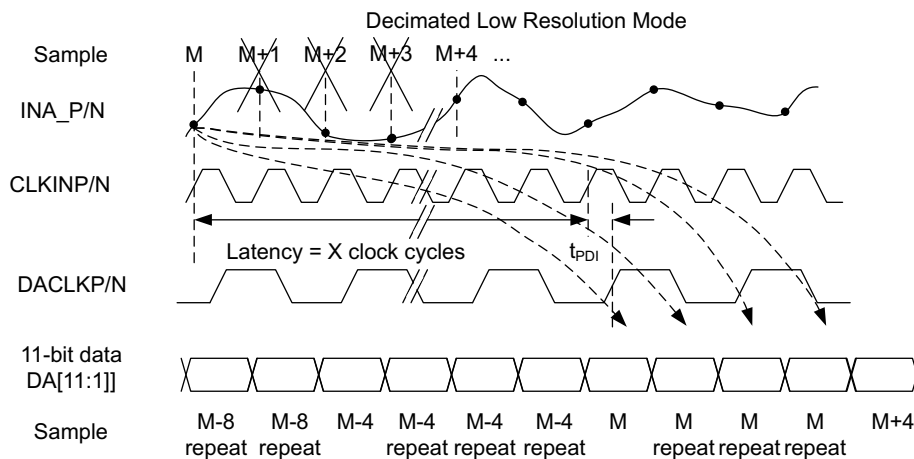
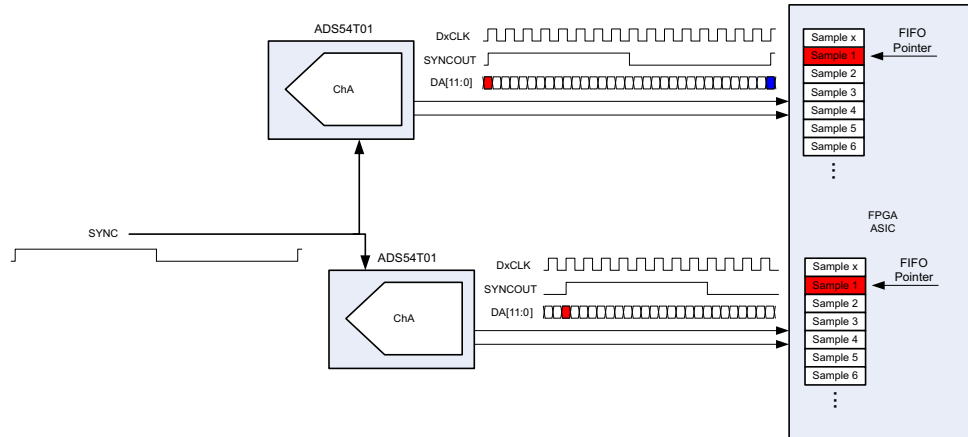


Figure 41. Decimated Low Resolution Output Data Timing Diagram

MULTI DEVICE SYNCHRONIZATION

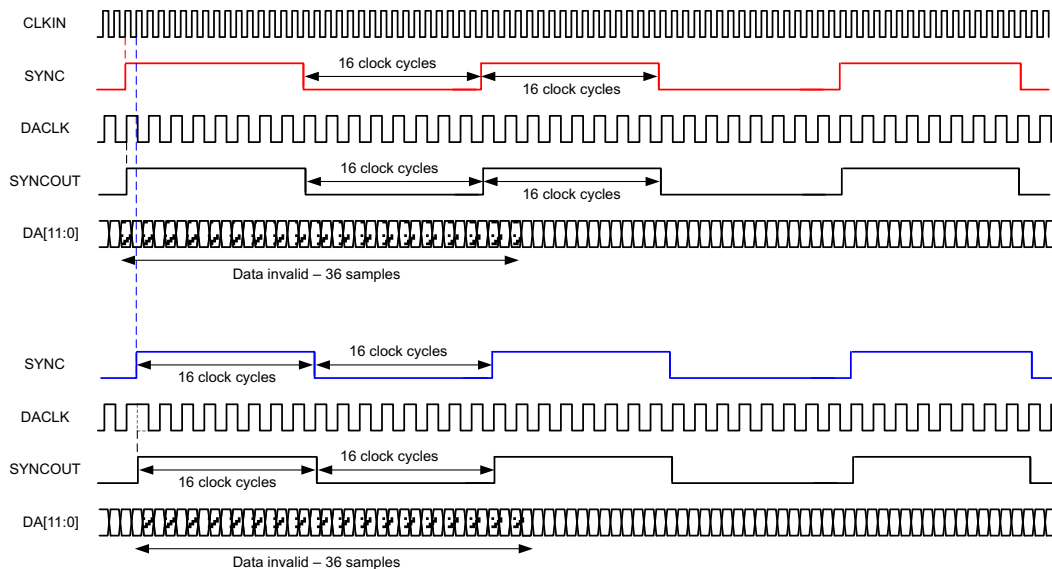
The ADS54T01 simplifies the synchronization of data from multiple ADCs in one common receiver. Upon receiving the initial SYNC input signal, the ADS54T01 resets all the internal clocks and digital logic while also starting a SYNCOUT signal which operates on a 5bit counter (32 clock cycles). Therefore by providing a common SYNC signal to multiple ADCs their output data can be synchronized as the SYNCOUT signal marks a specific sample with the same latency in all ADCs. The SYNCOUT signal then can be used in the receiving device to synchronize the FIFO pointers across the different input data streams. Thus the output data of multiple ADCs can be aligned properly even if there are different trace lengths between the different ADCs.



The SYNC input signal should be a one time pulse to trigger the periodic 5-bit counter for SYNCOUT or a periodic signal repeating every 32 CLKIN clock cycles. It gets registered on the rising edge of the ADC input clock (CLKIN). Upon registering the initial rising edge of the SYNC signal, the internal clocks and logic get reset which results in invalid output data for 36 samples (1 complete sync cycle and 4 additional samples). The SYNCOUT signal starts with the next output clock (DACLK) rising edge and operates on a 5-bit counter. If a SYNCIN rising edge gets registered at a new position, the counter gets reset and SYNCOUT starts from the new position.

Since the ADS54T01 output interface operates with a DDR clock, the synchronization can happen on the rising edge or falling edge sample. Synchronization on the falling edge sample will result in a half cycle clock stretch of DACLK. For convenience the SYNCOUT signal is available on the ChA output LVDS bus.

When using decimation the SYNCOUT signal still operates on 32 clock cycles of CLKIN but since the output data is decimated by 2, only the first 18 samples should be discarded.



PROGRAMMING INTERFACE

The serial interface (SIF) included in the ADS54T01 is a simple 3 or 4 pin interface. In normal mode, 3 pins are used to communicate with the device. There is an enable (SDENB), a clock (SCLK) and a bi-directional IO port (SDIO). If the user would like to use the 4 pin interface one write must be implemented in the 3 pin mode to enable 4 pin communications. In this mode, the SDO pin becomes the dedicated output. The serial interface has an 8-bit address word and a 16-bit data word. The first rising edge of SCLK after SDENB goes low will latch the read/write bit. If a high is registered then a read is requested, if it is low then a write is requested. SDENB must be brought high again before another transfer can be requested. The signal diagram is shown below:

Device Initialization

After power up, it is recommended to initialize the device through a hardware reset by applying a logic low pulse on the SRESETb pin (of width greater than 20ns), as shown in Figure 42. This resets all internal digital blocks (including SPI registers) to their default condition.

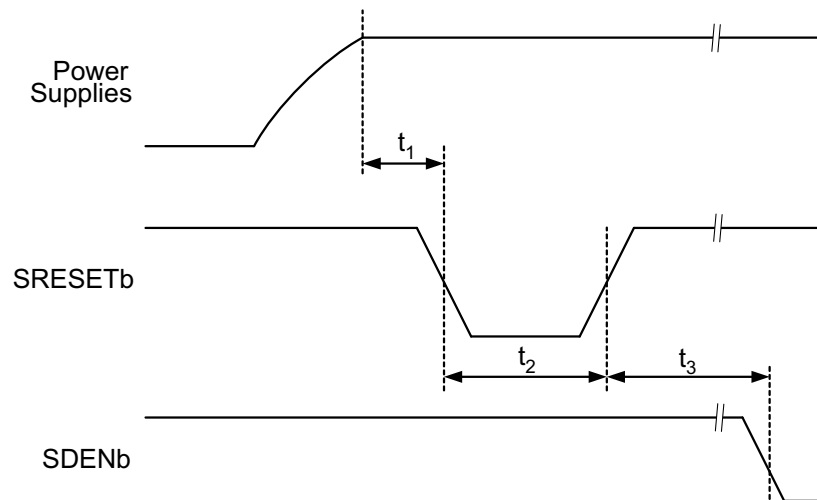


Figure 42. Device Initialization Timing Diagram

Table 1. Reset Timing

PARAMETER		CONDITIONS	MIN	TYP	MAX	UNIT
t ₁	Power-on delay	Delay from power up to active low RESET pulse	3			ms
t ₂	Reset pulse width	Active low RESET pulse width	20			ns
t ₃	Register write delay	Delay from RESET disable to SDENb active	100			ns

Recommended Device Initialization Sequence:

1. Power up
2. Reset ADS54T01 using hardware reset.
3. Apply clock and input signal.
4. Set register 0x01 bit D15 to "1" (ChA Corr EN) to enable gain/offset correction circuit and other desired registers.
5. Set register 0x03 bit D14 to "1" (Start Auto Corr ChA). This clears and resets the accumulator values in the DC and gain correction loop.
6. Set register 0x03 bit D14 to "0" (Start Auto Corr ChA). This starts the DC and gain auto-correction loop.

Serial Register Write

The internal register of the ADS54T01 can be programmed following these steps:

1. Drive SDENB pin low
2. Set the R/W bit to '0' (bit A7 of the 8 bit address)

3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be written
4. Write 16bit data which is latched on the rising edge of SCLK

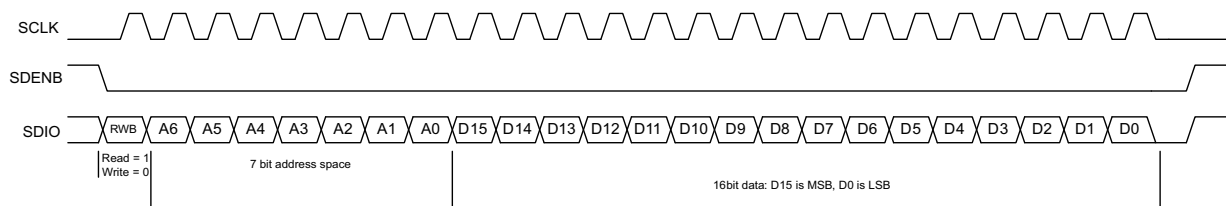


Figure 43. Serial Register Write Timing Diagram

PARAMETER		MIN	TYP ⁽¹⁾	MAX	UNIT
f_{SCLK}	SCLK frequency (equal to $1/t_{\text{SCLK}}$)	>DC		20	MHz
t_{SLOADS}	SDENB to SCLK setup time	25			ns
t_{SLOADH}	SCLK to SDENB hold time	25			ns
t_{DSU}	SDIO setup time	25			ns
t_{DH}	SDIO hold time	25			ns

- (1) Typical values at +25°C; minimum and maximum values across the full temperature range: TMIN = –40°C to TMAX = +85°C, AVDD3V = 3.3V, AVDD, DRVDD = 1.9V, unless otherwise noted.

Serial Register Readout

The device includes a mode where the contents of the internal registers can be read back using the SDO/SDIO pins. This read-back mode may be useful as a diagnostic check to verify the serial interface communication between the external controller and the ADC.

1. Drive SDENB pin low
2. Set the RW bit (A7) to '1'. This setting disables any further writes to the registers
3. Initiate a serial interface cycle specifying the address of the register (A6 to A0) whose content has to be read.
4. The device outputs the contents (D15 to D0) of the selected register on the SDO/SDIO pin
5. The external controller can latch the contents at the SCLK rising edge.
6. To enable register writes, reset the RW register bit to '0'.

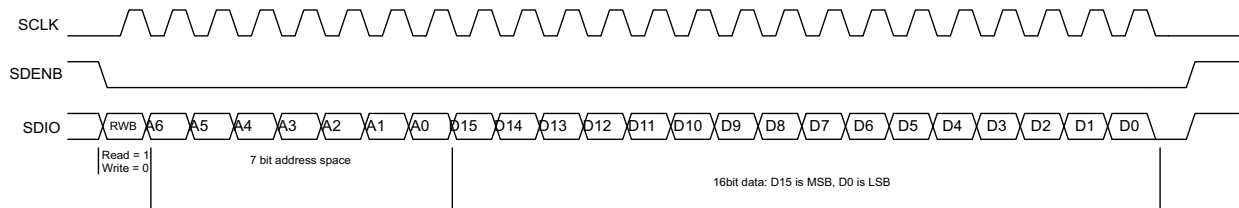


Figure 44. Serial Register Read Timing Diagram

SERIAL REGISTER MAP⁽²⁾

(2) Multiple functions in a register can be programmed in a single write operation.

Register Address	Register Data															
A7-A0 IN HEX	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	DecFil/ Burst	0	High/ Low Pass	0	0	0	0	0	0	Burst rate	0	0	Auto Trigger	0	0
1	Corr EN	0	0	0	0	0	0	0	0	0	0	0	Data Format	0	Hp Mode1	0
2	0	1	1	0	0	Over-range threshold				0	0	0	0	0	0	0
3	0	DC Offset Corr	0	0	1	0	1	1	0	0	0	1	1	0	0	0
E	Sync Select														0	0
F	Sync Select				0	0	0	0	0	VREF Set			0	0	0	0
1A	0	0	0	0	1	0	1	1	0	0	0	1	1	0	0	0
2B	0	0	0	0	0	0	0	Temp Sensor								
2C	Reset															
34	0	0	Burst Mode N				0	0	0	0	0	0	0	0	0	0
37	Sleep Modes						0	0	0	0	0	0	0	0	0	0
38	HP Mode2							LP Mode	TEMP EN	BIAS EN	SYNC EN	TRIGEN	1	1	1	1
3A	LVDS Current Strength			LVDS SW		Internal LVDS Termination		0	0	0	0	DACLK EN	DBCLK EN	0	OVRA EN	OVRB EN
66	LVDS Output Bus A EN															

DESCRIPTION OF SERIAL INTERFACE REGISTERS

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
0	3/4 Wire SPI	Dec Fil/ Burst	0	High/ Low Pass	0	0	0	0	0	0	Burst rate	0	0	Auto Trigger	0	0

- D15 3/4 Wire SPI** Enables 4-bit serial interface when set
Default 0
- 0 3 wire SPI is used with SDIO pin operating as bi-directional I/O port
- 1 4 wire SPI is used with SDIO pin operating as data input and SDO pin as data output port.
- D14 DecFil/ Burst** 2x decimation filter (Receive Mode) is enabled when bit is set
Default 0
- 0 Burst mode enable
- 1 2x decimation filter enabled
- D12 High/Low Pass** (Decimation filter must be enabled first: set bit D14)
Default 0
- 0 Low Pass
- 1 High Pass
- D5 Burst Rate** Low resolution output data rate in burst mode
Default 0
- 0 Low resolution (9bit) full output rate
- 1 Decimated low resolution output (4x decimation, 11bit resolution)

- D2 Auto Trigger** Enables auto trigger mode in burst mode without the need to control the trigger pin.
Default 0
- 0 Manual trigger mode using the external trigger input pin
- 1 Auto trigger mode enabled

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1	Corr EN	0	0	0	0	0	0	0	0	0	0	0	Data Format	0	HP Mode 1	0

- D15 Corr EN (should be enabled for maximum performance)**
Default 0
- 0 auto gain correction disabled
- 1 auto gain correction enabled
- D3 Data Format**
Default 0
- 0 Two's complement
- 1 Offset Binary
- D1 HP Mode 1**
Default 0
- 1 Must be set to 1 for optimum performance

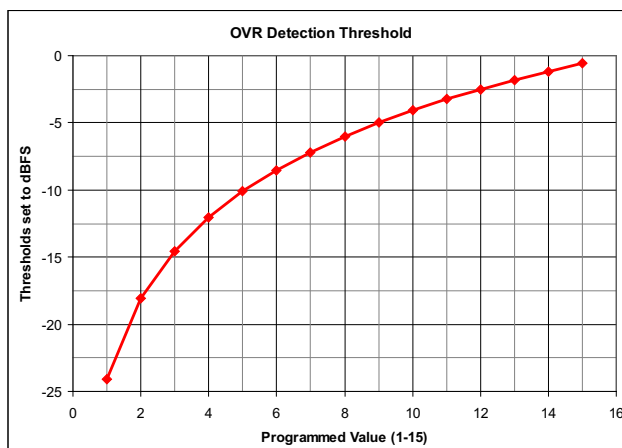
Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2	0	1	1	0	0	Over-range threshold				0	0	0	0	0	0	0

D14 Read back 1.

D13 Read back 1.

- D10-D7 Over-range threshold** The over-range detection is triggered 12 output clock cycles after the overload condition occurs. The threshold at which the OVR is triggered = $1.0V \times [\text{decimal value of } \langle \text{Over-range threshold} \rangle] / 16$. After power up or reset, the default value is 15 (decimal) which corresponds to a OVR threshold of 0.56dB below fullscale ($20 \times \log(15/16)$). This OVR threshold is applicable to both channels.

Default 1111



Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3	0	DC Offset Cof	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14 **DC Offset Corr** Starts DC offset correction loop
 Default 1

0 Starts offset correction loop

1 DC offset correction loop is cleared

D11, 9, 8, 4, 3 Must be set to 1 for maximum performance
 Default 1

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
E	Sync Select														0	0

D15-D2 **Sync Select** Sync selection for the clock generator block (also
 Default 1010 1010 need to see address 0x0F)
 1010 10

0000 0000 0000 00 Sync is disabled

0101 0101 0101 01 Sync is set to one shot (one time synchronization only)

1010 1010 1010 10 Sync is derived from SYNC input pins

1111 1111 1111 11 not supported

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
F	Sync Select				0	0	0	0	0	VREF Sel			0	0	0	0

D15-D12 **Sync Select** Sync selection for the clock generator block

Default 1010 1010 1010
10

0000 Sync is disabled

0101 Sync is set to one shot (one time synchronization only)

1010 Sync is derived from SYNC input pins

1111 not supported

D6-D4 **VREF SEL** Internal voltage reference selection

Default 000

000 1.0V

001 1.25V

010 0.9V

011 0.8V

100 1.15V

Others external reference

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
1A	0	0	0	0	1	0	1	1	0	0	0	1	1	0	0	0

D14, 11, 9, 8, 4, Must be set to 1 for maximum performance
3 Default 1

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2B	0	0	0	0	0	0	0	Temp Sensor								

D8-D0 **Temp Sensor** Internal temperature sensor value – read only

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
2C	Reset															

D15-D0 **Reset** This is a software reset to reset all SPI registers to their default value. Self
Default clears to 0.
0000

1101001011110000 Perform software reset

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
34	0	0	Burst Mode N				0	0	0	0	0	0	0	0	0	0

D13-D10 Burst Mode N This is the parameter that sets the amount of high resolution samples in burst mode
 Default 0000
 0000 N = 10
 0001 N = 11
 ...
 1111 N = 25

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
37	Sleep Modes						0	0	0	0	0	0	0	0	0	0

D15-D14 Sleep Modes Sleep mode selection which is controlled by the ENABLE pin. Sleep modes are active when ENABLE pin goes low.
 Default 00
 000000 Complete shut down Wake up time 2.5 ms
 100000 Stand-by mode Wake up time 100 μ s
 110000 Deep sleep mode Wake up time 20 μ s
 110101 Light sleep mode Wake up time 2 μ s

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
38	HP Mode 2							LP Mode	TEMP EN	FUSE Bias EN	SYNC EN	TRIG EN	1	1	1	1

D15-D9 HP Mode 2

Default 111111111

1 Set to 1 for normal operation

D8 LP Mode Low power mode

Default 1

0 Set to 0 to turn off unused output buffers

D7 TEMP EN Temperature sensor enable

Default 1

1 Set to 1 to enable the temperature sensor

D6 FUSE BIAS EN Enables internal bias voltages. Can be disabled after power up for power savings.

Default 1

0 Internal fuse bias powered down

1 Internal fuse bias enabled

D5 SYNC EN Enables the SYNC input buffer.

Default 1

0 SYNC input buffer disabled

1 SYNC input bffer enabled

D4 TRIG EN Enables the TRIGGER input buffer.

Default 1

0 TRIGGER input buffer disabled

1 TRIGGER input bffer enabled

D3-D0 Read back 1

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
3A	LVDS Current Strength			LVDS SW		Internal LVDS Termination		0	0	0	0	DACLK EN	0	0	OVRA EN	0

D15-D13	LVDS Current Strength	LVDS output current strength.		
	Default 000			
000	2 mA	100	3 mA	
001	2.25 mA	101	3.25 mA	
010	2.5 mA	110	3.5 mA	
011	2.75 mA	111	3.75 mA	
D12-D11	LVDS SW	LVDS driver internal switch setting – correct range must be set for setting in D15-D13		
	Default 01			
01	2 mA to 2.75 mA			
11	3mA to 3.75mA			
D10-D9	Internal LVDS Termination	Internal termination		
	Default 00			
00	2 kΩ			
01	200 Ω			
10	200 Ω			
11	100 Ω			
D4	DACLK EN	Enable DACLK output buffer		
	Default 1			
0	DACLK output buffer powered down			
1	DACLK output buffer enabled			
D1	OVRA EN	Enable OVRA output buffer		
	Default 1			
0	OVRA output buffer powered down			
1	OVRA output buffer enabled			

Register Address	Register Data															
A7-A0 in hex	D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
66	LVDS Output Bus EN															

D15-D0	LVDS Output Bus EN	Individual LVDS output pin power down
	Default FFFF	
0	Output is powered down	
1	Output is enabled	
D15	corresponds to TRDYP/N (pins N7, P7)	
D14	corresponds to HRESP/N (pins N6, P6)	
D13	SYNCOUTP/N (pins N5, P5)	
D12	Pins N4, P4 (no connect pins) which are not used and should be powered down for power savings	
D11-D0	corresponds to DA11-DA0	

REVISION HISTORY

Changes from Original (December 2012) to Revision A	Page
• Deleted P7, N7 from TRDYP/N pin numbers	4
• Changed package from QFN to nFBGA in THERMAL INFORMATION	5
• Added text and figure to TEST PATTERN OUTPUT section	20
• Deleted text from last paragraph in INTERLEAVING CORRECTION section	23
• Changed second paragraph in MULTI DEVICE SYNCHRONIZATION section	28
• Deleted Register Initialization section and added Device Initialization section	29
• Changed Register Address 2 Bit D13 from 0 to 1 in SERIAL REGISTER MAP	32
• Changed Register Address E Bits D1 and D0 to 0 in SERIAL REGISTER MAP	32
• Changed Register Address 38 Bits D3 to D0 from 0 to 1 in SERIAL REGISTER MAP	32
• Changed Register Address 2 Bit D13 from 0 to 1 and add D13 Read back 1	33
• Changed Register Address E Bit D1 and D0 to 0	34
• Changed Register Address 38 Bits D3 to D0 from 0 to 1 and add D3 to D0 Read back 1	37

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
ADS54T01IZAY	ACTIVE	NFBGA	ZAY	196	160	RoHS & Green	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T01I	Samples
ADS54T01IZAYR	ACTIVE	NFBGA	ZAY	196	1000	RoHS & Green	SNAGCU	Level-3-260C-168 HR	-40 to 85	ADS54T01I	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBsolete: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

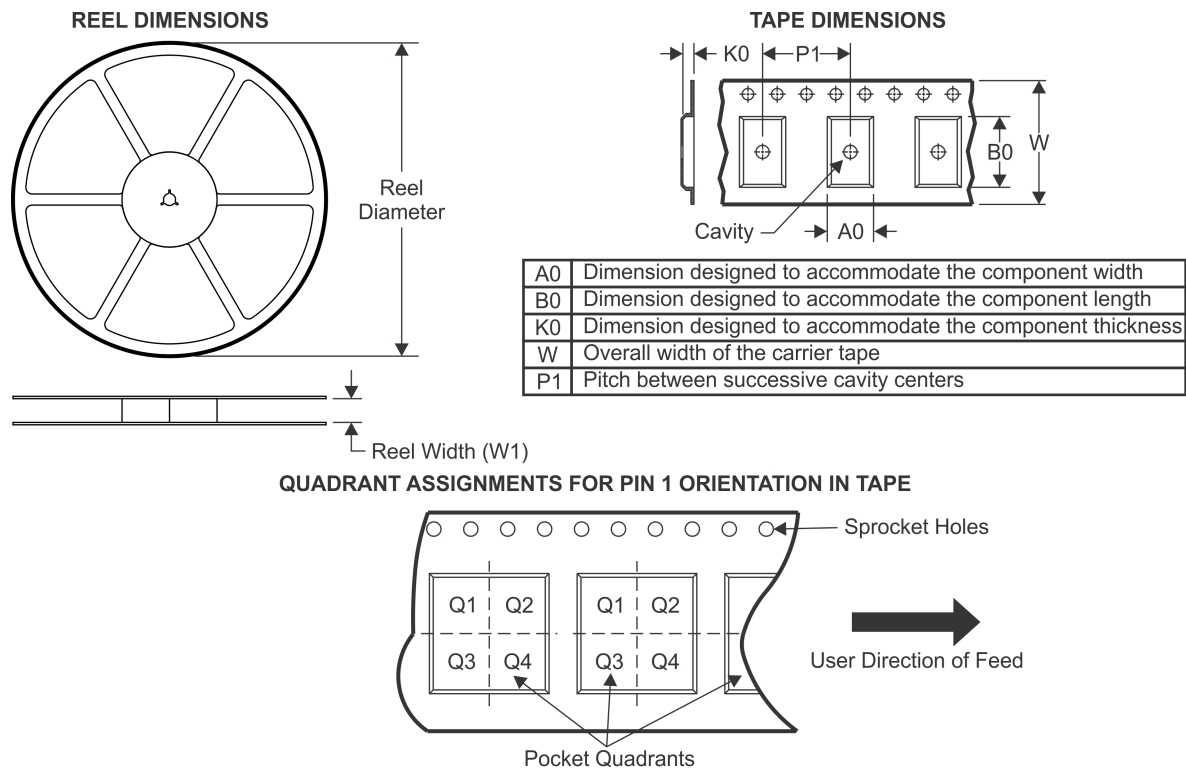
(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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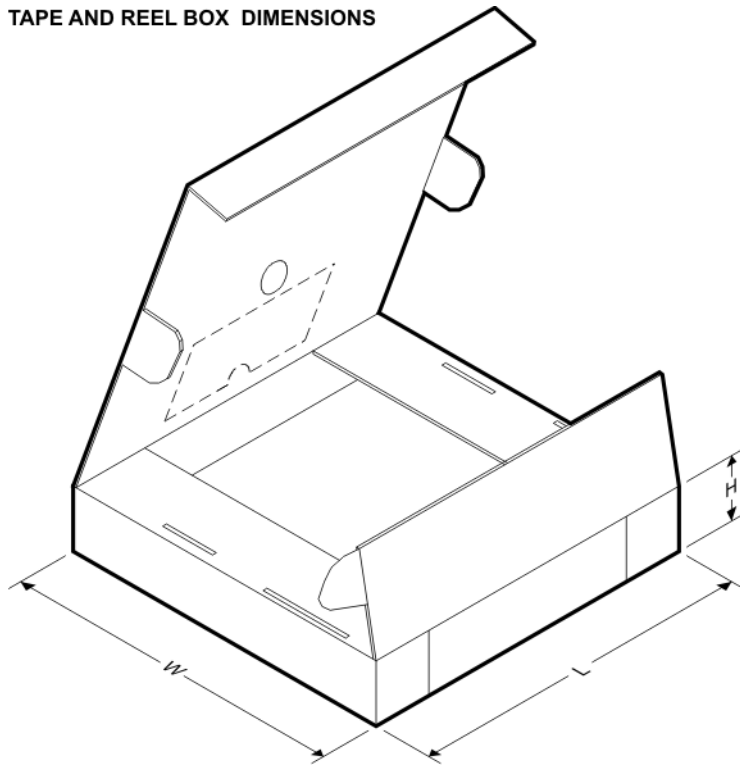
TAPE AND REEL INFORMATION



*All dimensions are nominal

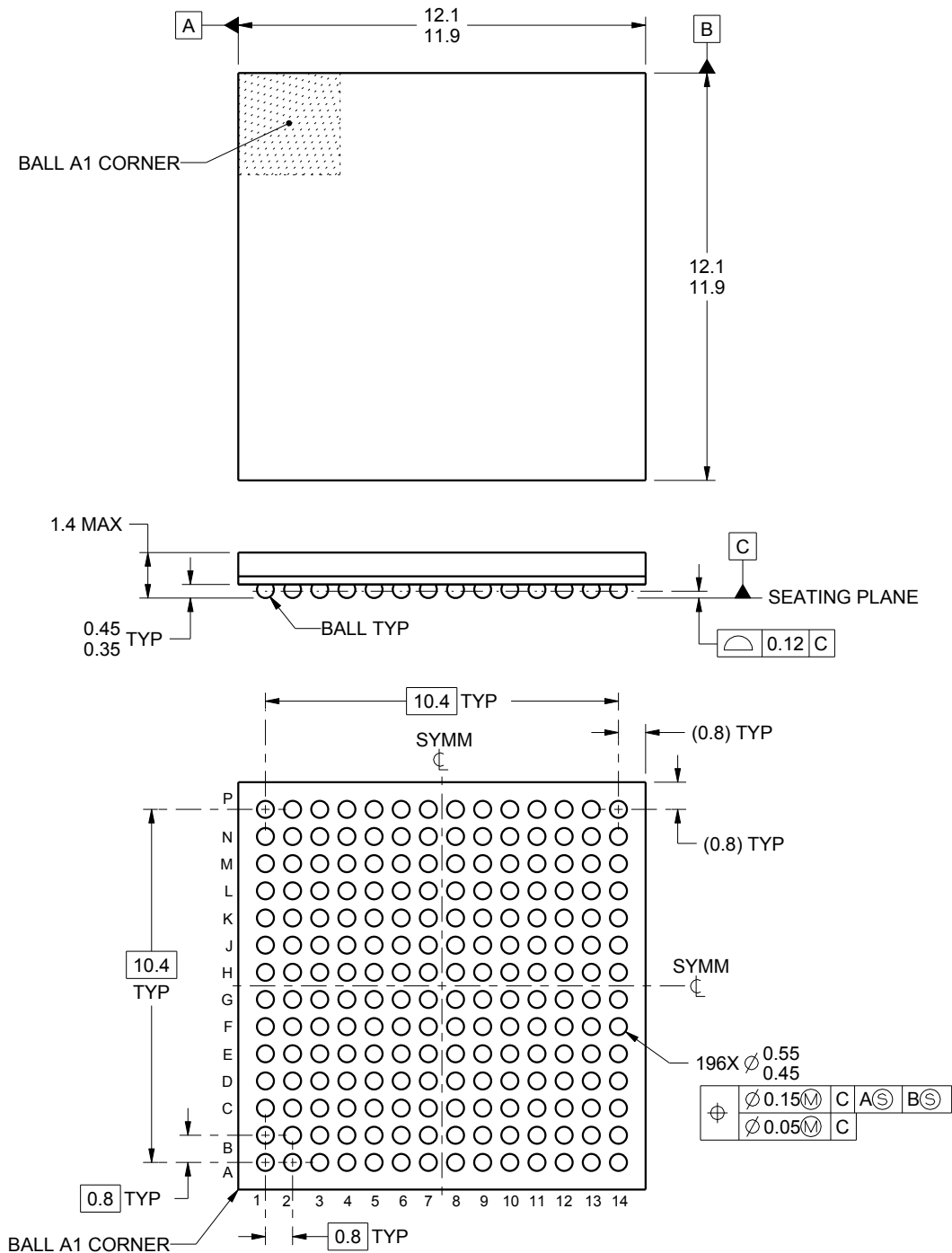
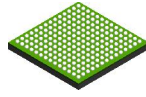
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ADS54T01IZAYR	NFBGA	ZAY	196	1000	330.0	24.4	12.3	12.3	2.3	16.0	24.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ADS54T01IZAYR	NFBGA	ZAY	196	1000	350.0	350.0	43.0



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NOTES:

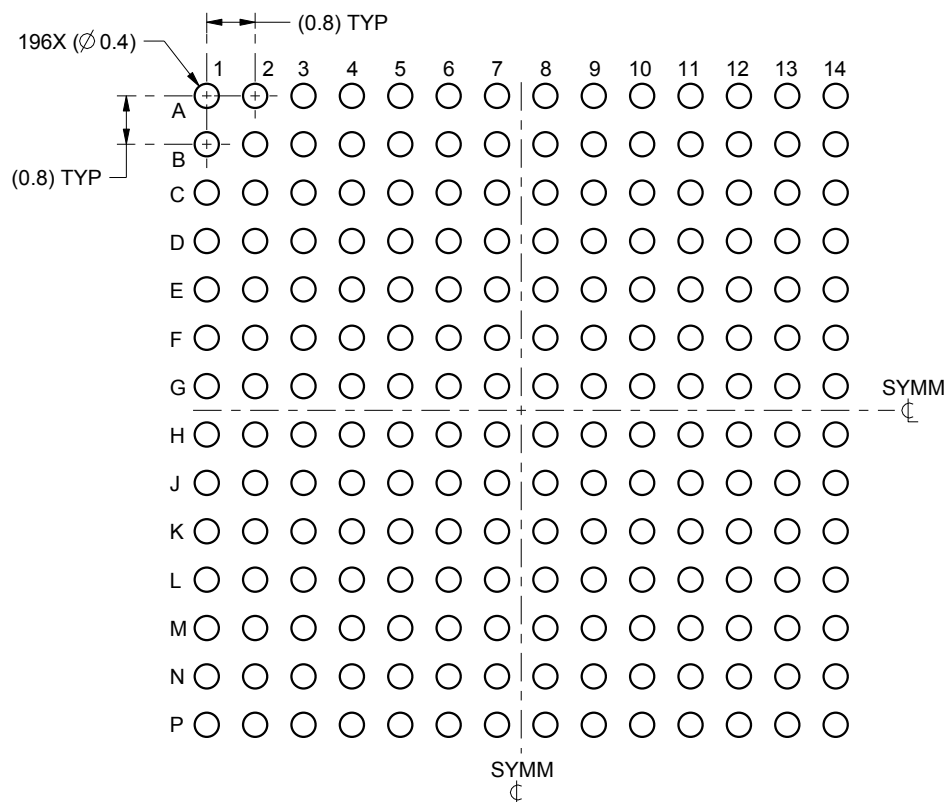
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.

EXAMPLE BOARD LAYOUT

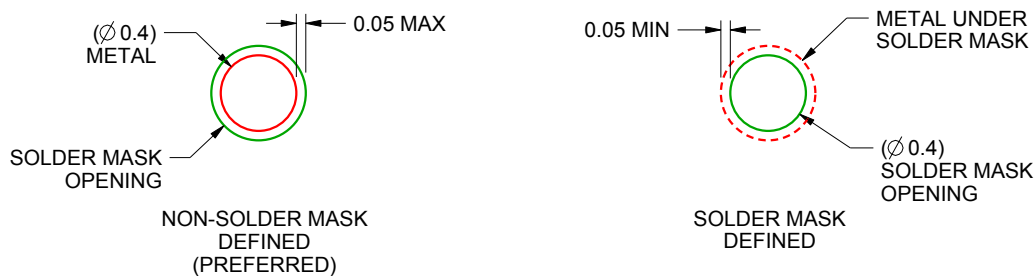
ZAY0196A

NFBGA - 1.4 mm max height

PLASTIC BALL GRID ARRAY



LAND PATTERN EXAMPLE
SCALE:8X



SOLDER MASK DETAILS
NOT TO SCALE

4219823/A 09/2015

NOTES: (continued)

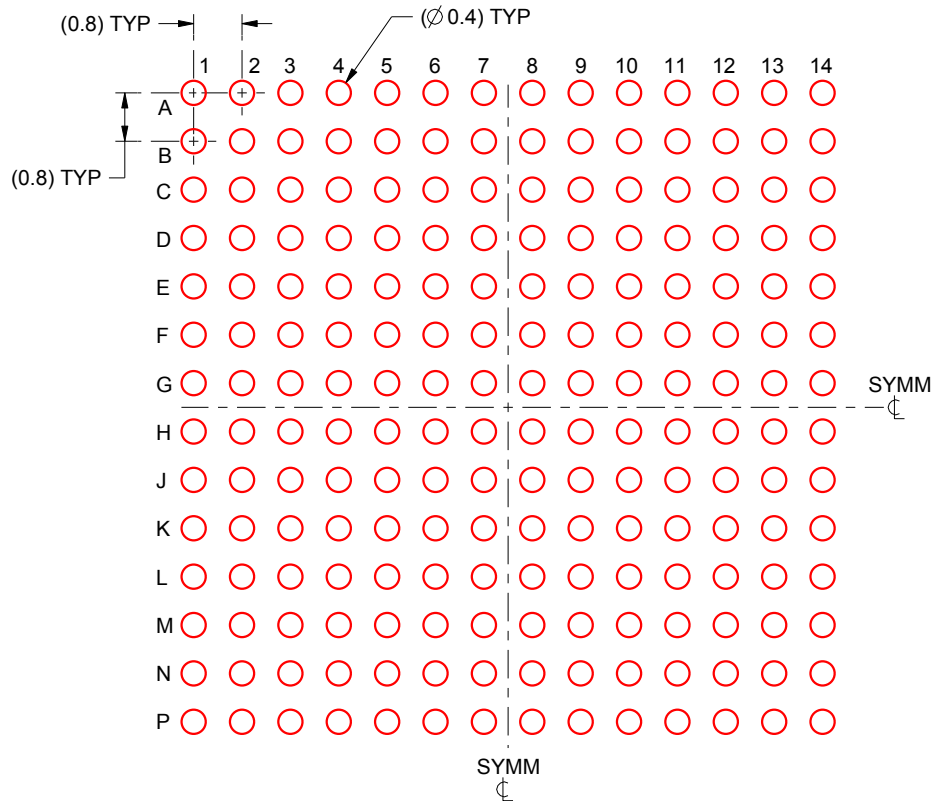
- Final dimensions may vary due to manufacturing tolerance considerations and also routing constraints. For information, see Texas Instruments literature number SPRAA99 (www.ti.com/lit/spraa99).

EXAMPLE STENCIL DESIGN

ZAY0196A

NFBGA - 1.4 mm max height

PLASTIC BALL GRID ARRAY



SOLDER PASTE EXAMPLE
BASED ON 0.15 mm THICK STENCIL
SCALE:8X

4219823/A 09/2015

NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release.

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